

- Trend of Advanced SiP - -Technology Development -

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System Solution Business Group
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8. SiP Mounting Technology
9. Stack SiP Development Trend
10. SiP Technology for Next Generation
 - CoC Technology -
11. Next Generation SiP Technology
 - Si Hole-Through Technology-

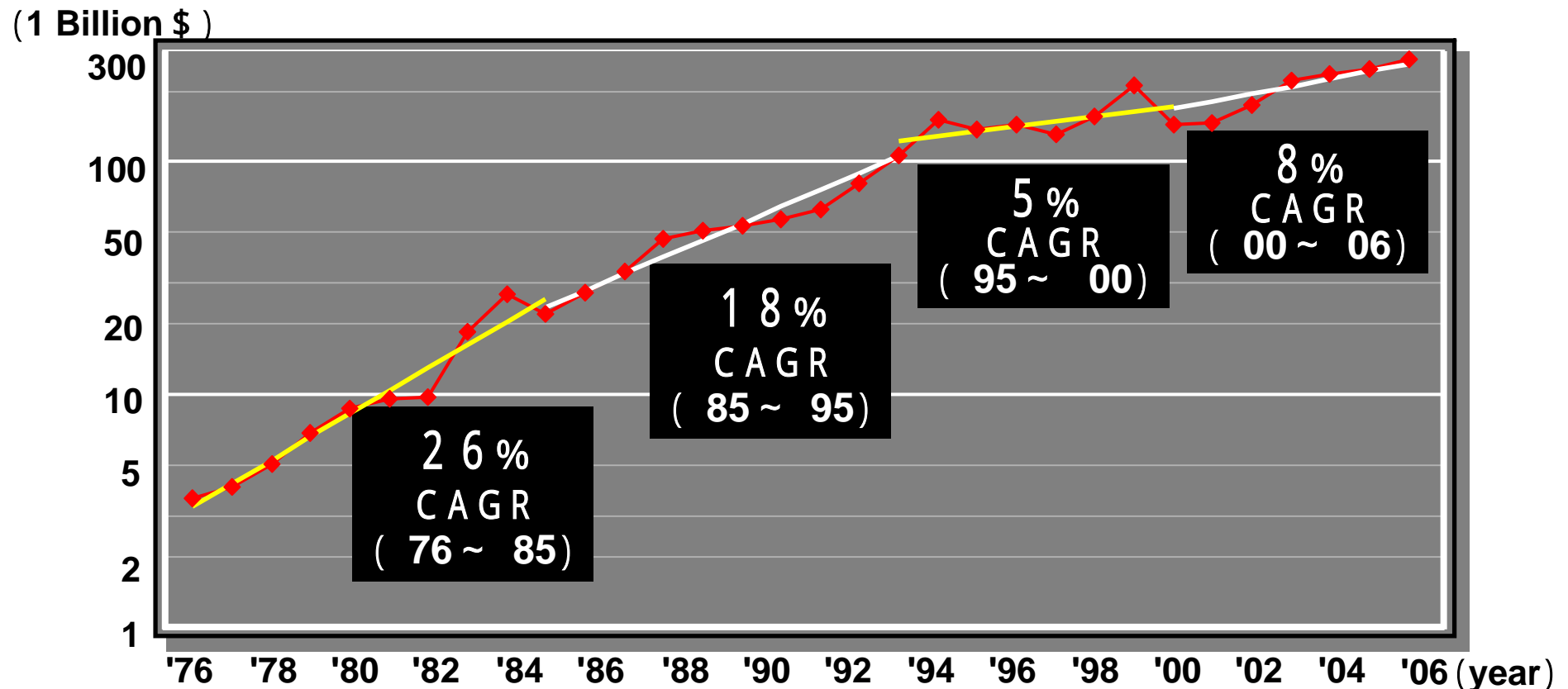
1 . Semiconductor Needs for Ubiquitous Network Era

Macro trend of growth rate at Semiconductor Market

The rate of market growth is tend to become slow

Action item is Determination of

“The Next Generation Growth Market” and Resource Concentration

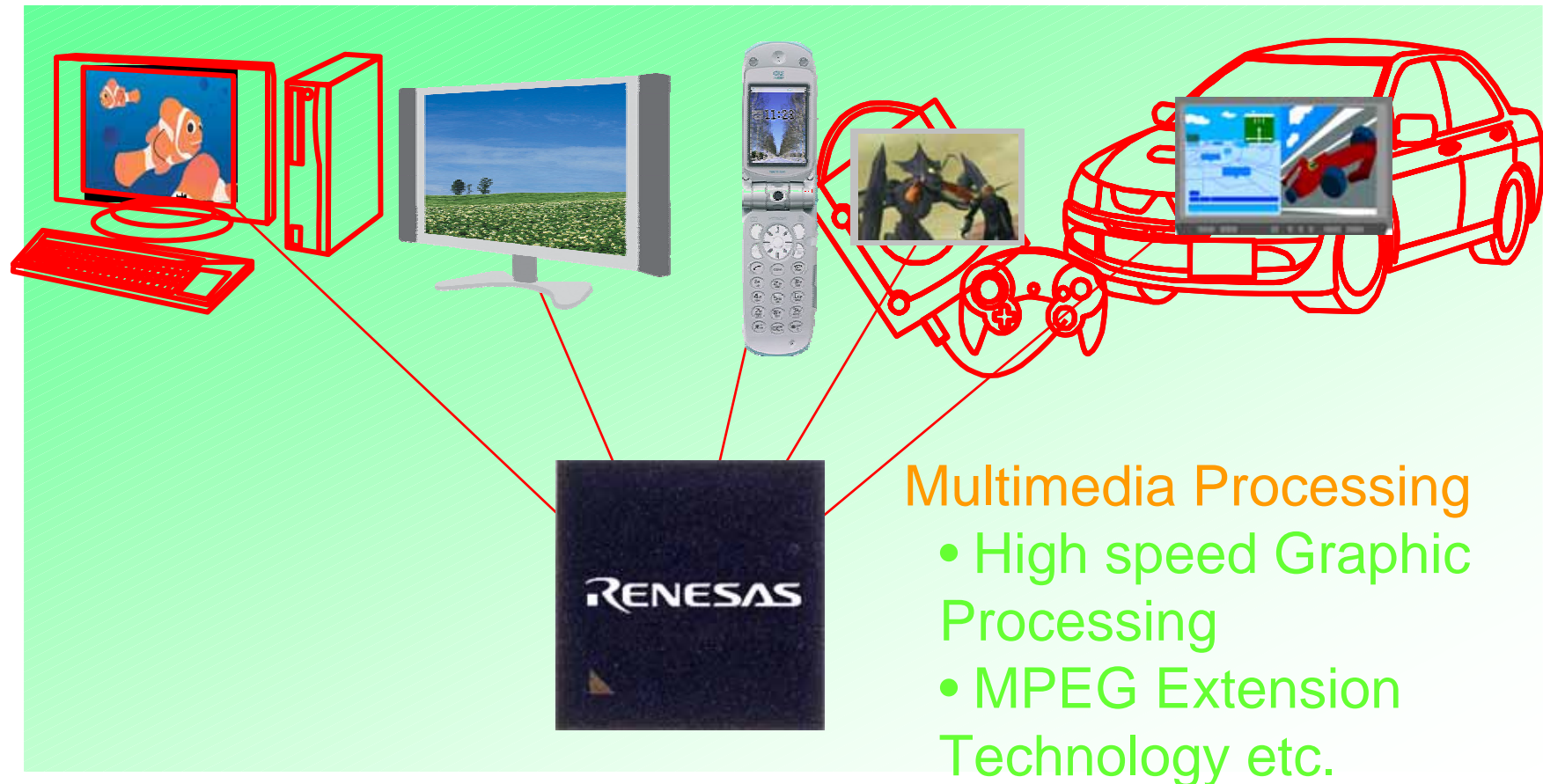


* CAGR is calculated after it approximates in order to decrease influence to Silicon Cycle.

Ref. :WSTS(2005.10)

Classification of Application and Convergence

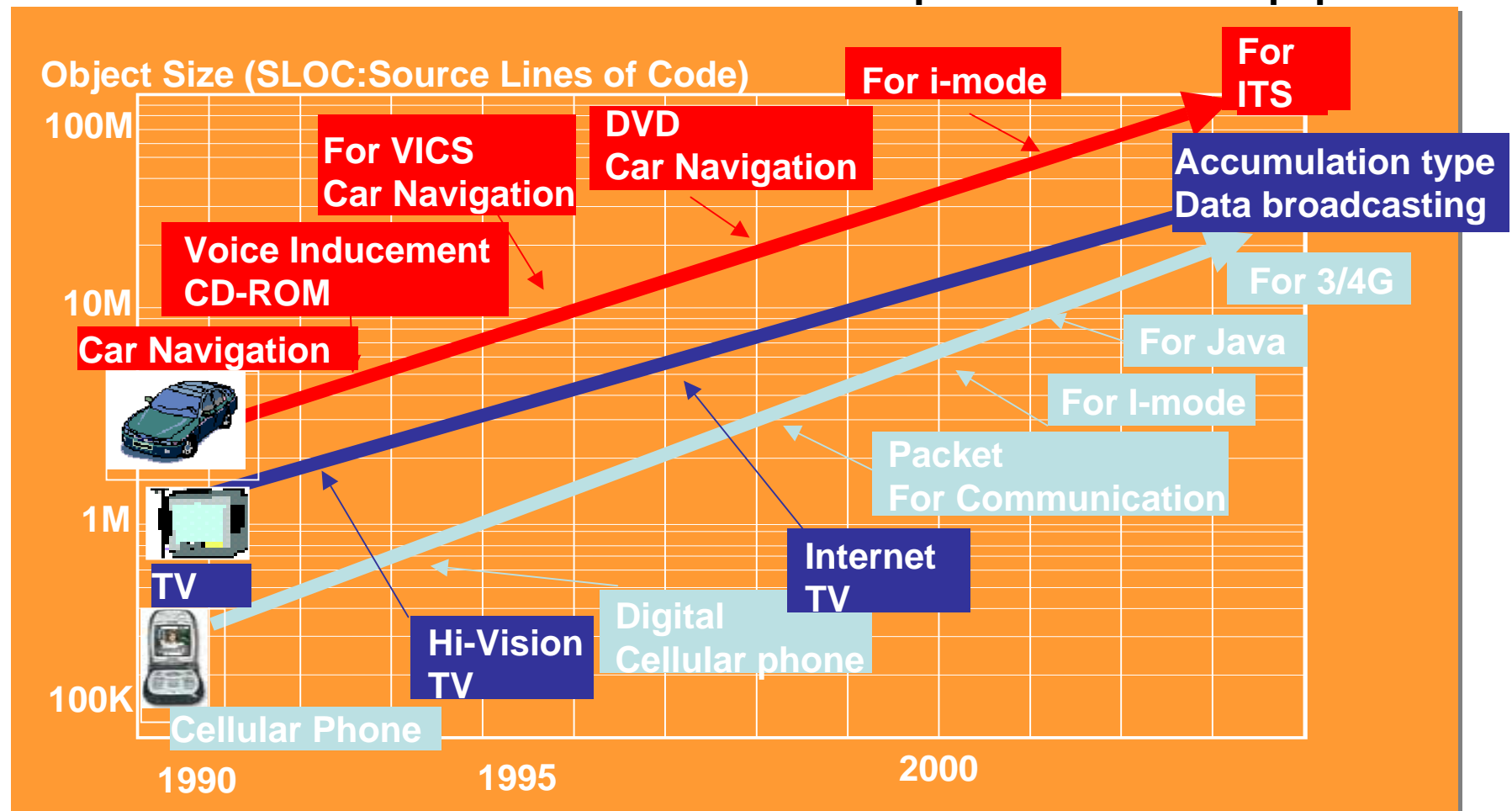
Developing function convergence such as Multimedia Processing and Network.
Continuity and development of Excellent Hard IP and Software IP become Important.



Huge Expansion of Application Software Development

Progressing Expansion of Software Development

in Ubiquitous Network Equipment

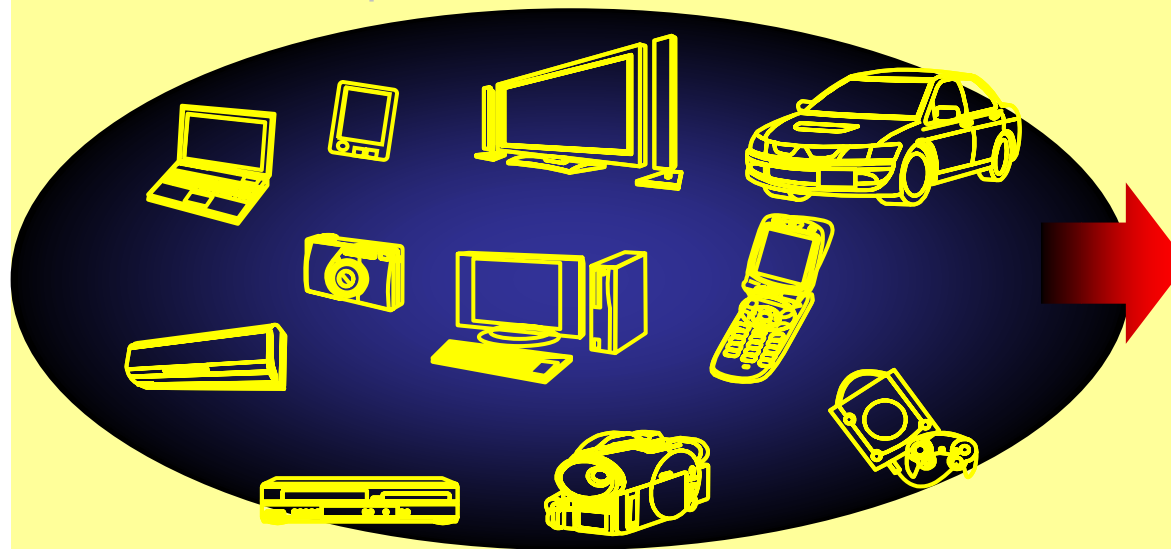


Source :IPA Information Processing System Society of Japan embedded system research Gr establishment commemoration symposium (July, '05)

Action item of Semiconductor System Solution

“Diversification”, which is Action item of Ubiquitous Network Equipment Semiconductor is required revenge of “Convergence”, “Development Expansion of Software”, “Short-term Development Cycle”

Ubiquitous Network Device



Device Action item Semiconductor Needs

For Diversification

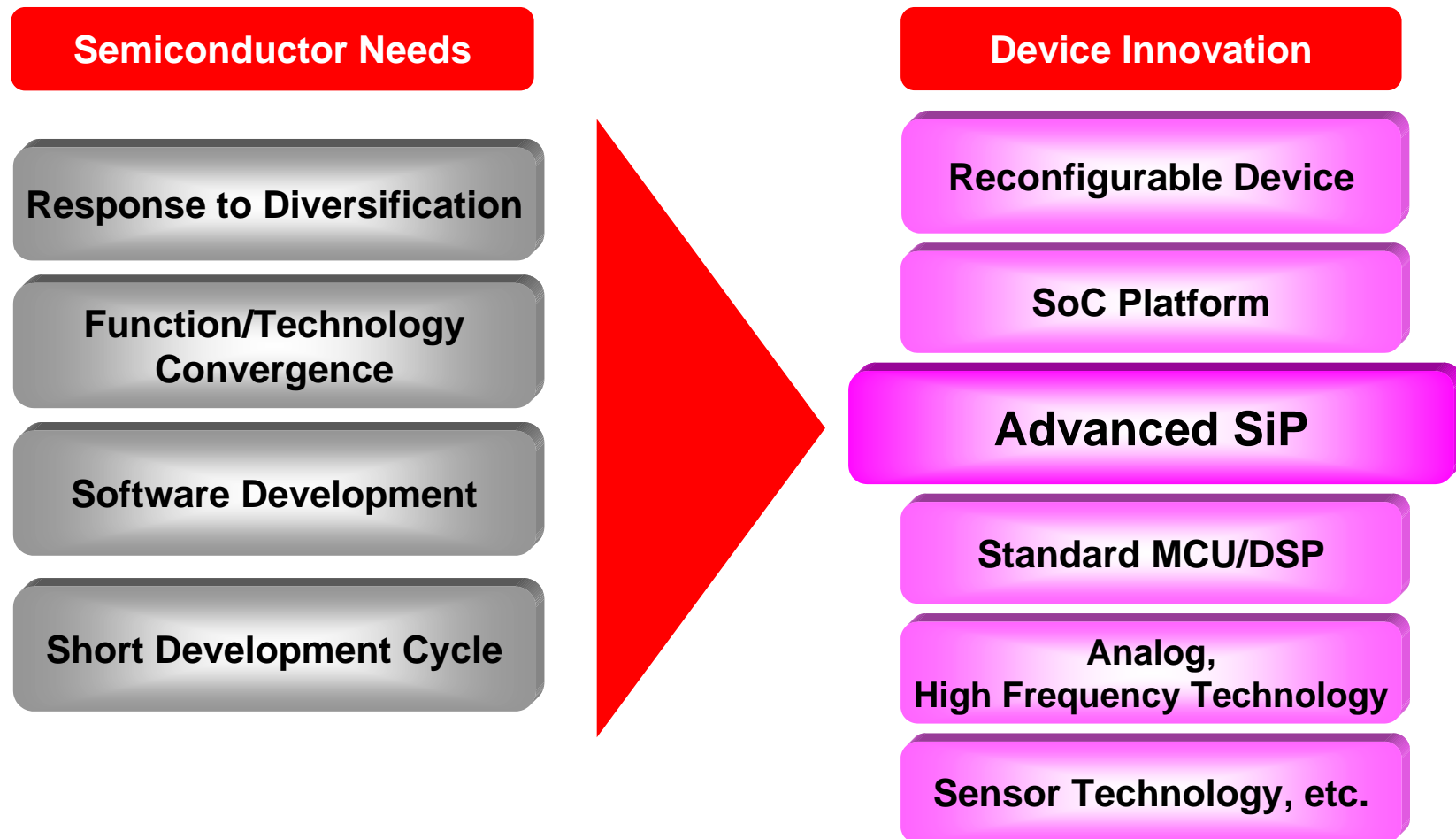
**Technology/Device
Convergence**

**Expansion of
Software Development**

**Development Cycle
Short-Term**

Device Innovation which realizes semiconductor needs in the ubiquitous generation

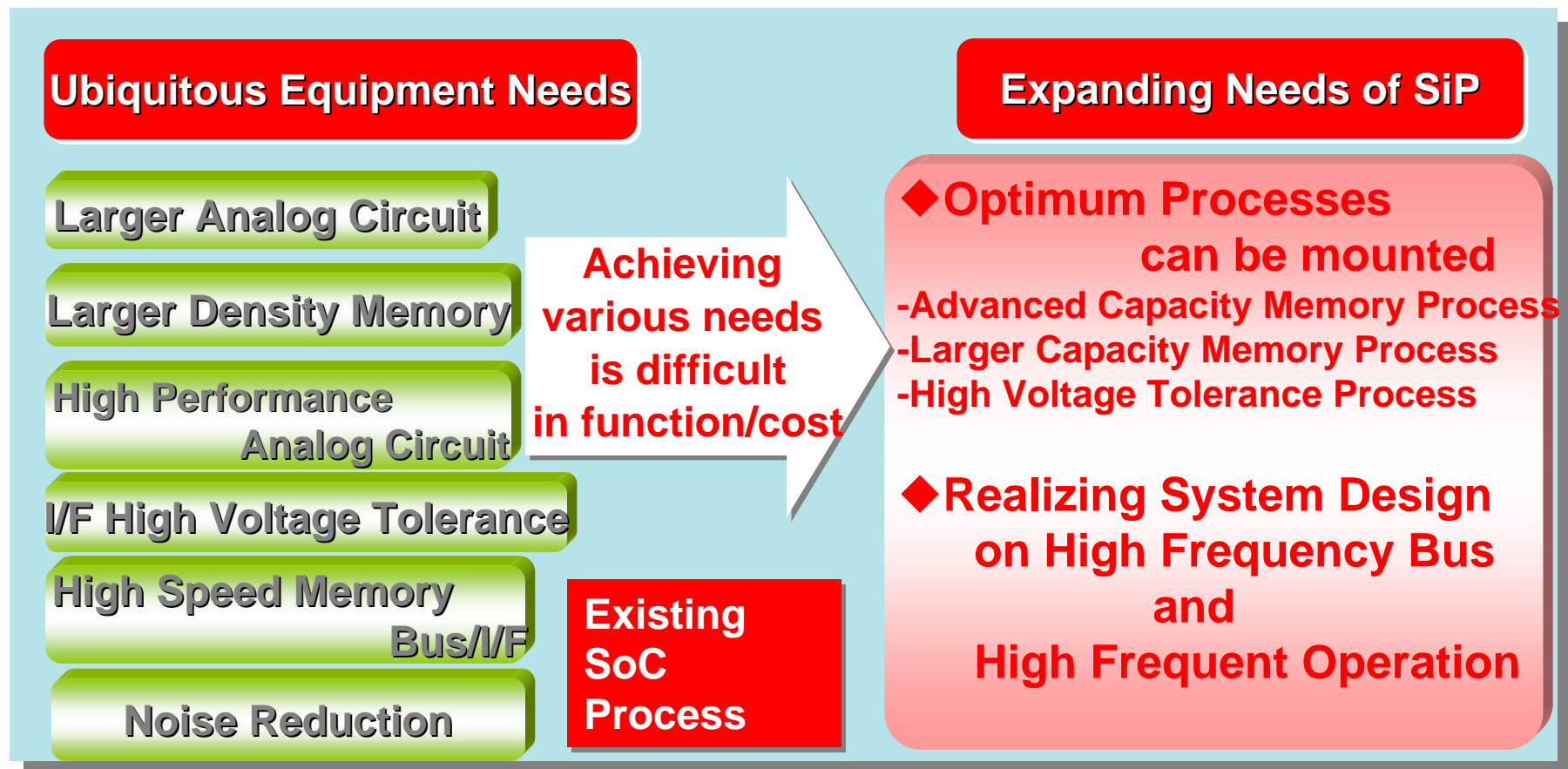
SoC Platform and **Advanced SiP** get more important



2. Approach toward System Solution

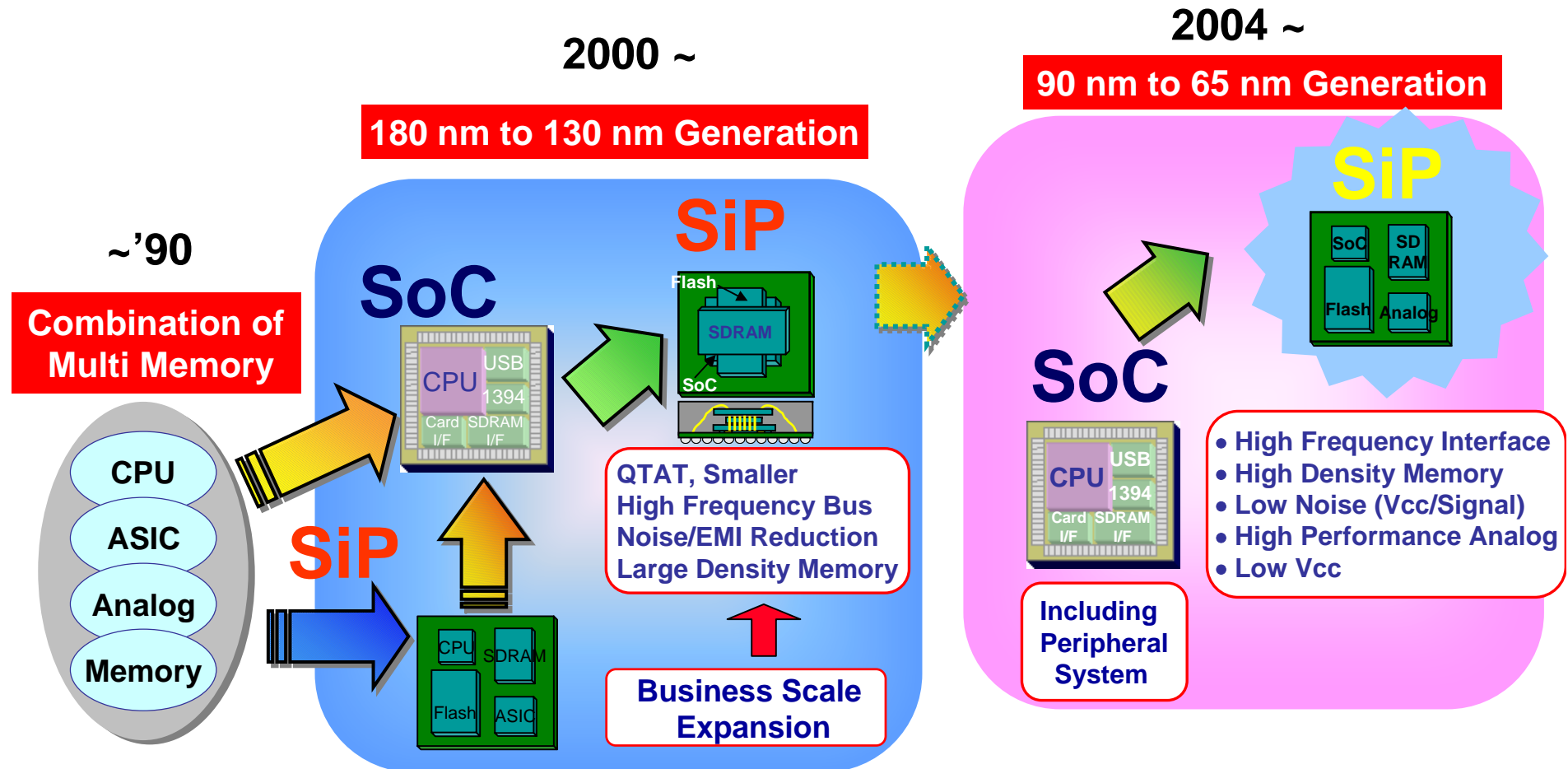
More Difficult Needs for SoC to Realize

- Larger Capacity Memory, High Frequency Bus and High Performance Analog Circuit are Required to Realize Ubiquitous Equipment
- Realize the best solution with SiP to combine High Powered SoC, Mass Memory and Highly Accurate



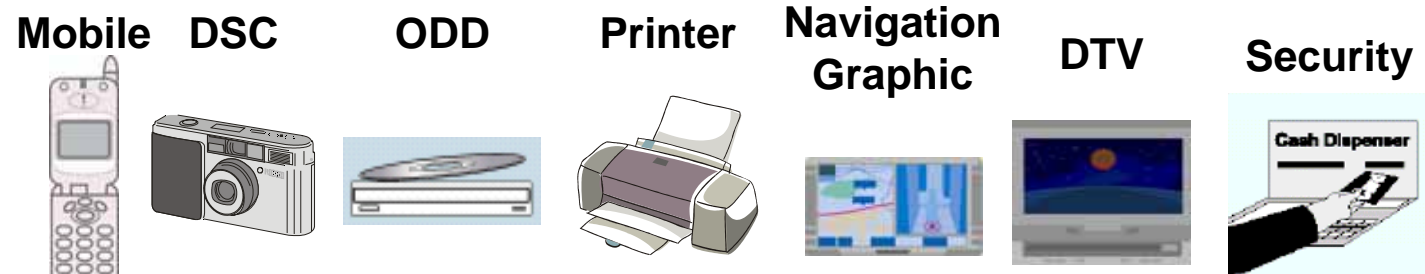
System LSI Business Trend

SiP can drive Maximum Performance for SoC



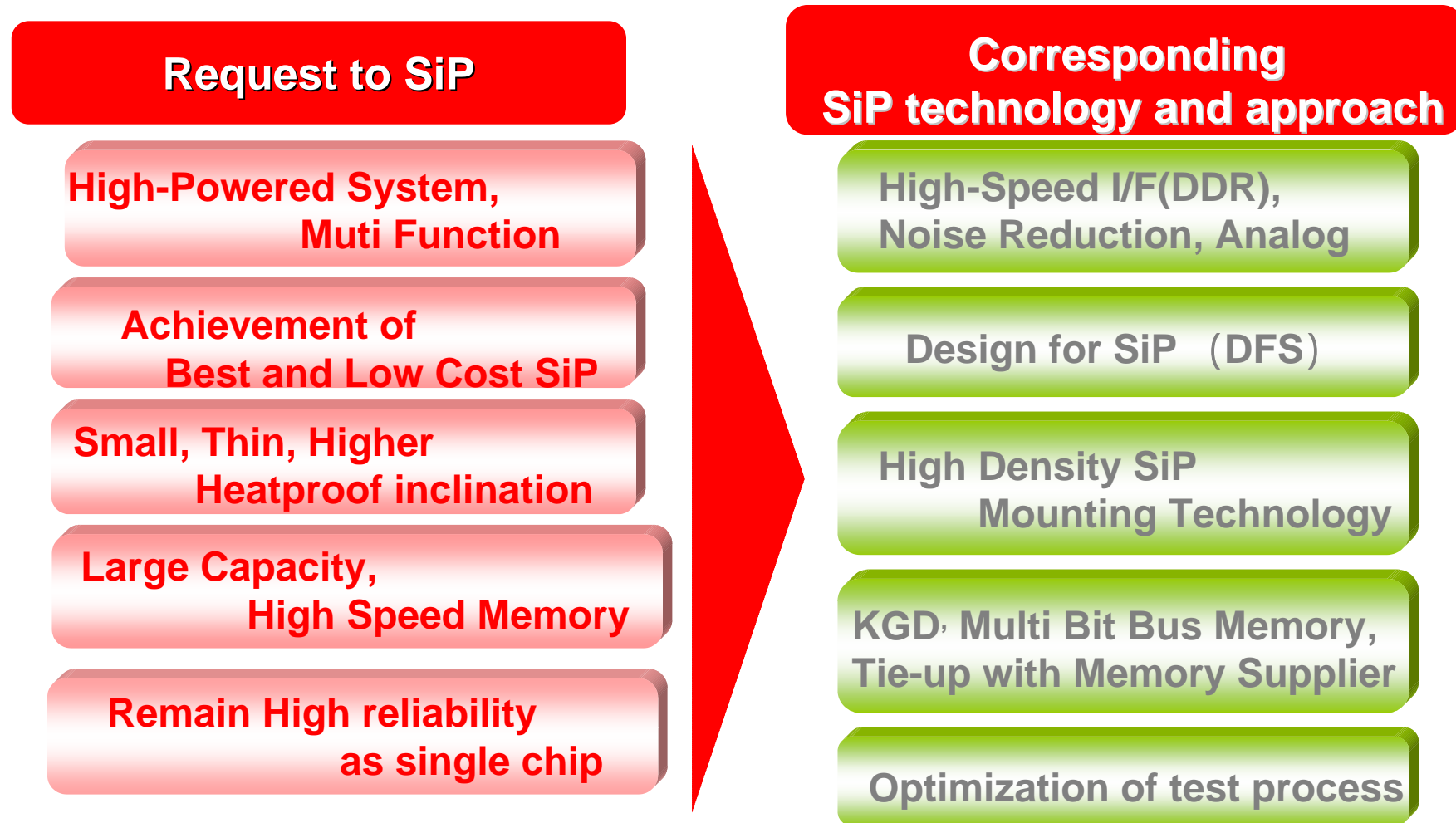
SiP Technology Realizes Various Application Needs

~ SiP Realizes Various Advanced Applications ~



SiP Advantages	Mobile	DSC	ODD	Printer	Navigation Graphic	DTV	Security
Small, Thin, Lightweight	●	●	●				●
EMI Noise Reduction		●		●	●	●	
Easy Design for High Frequency Bus		●			●	●	
Standardization for Customer System Board and Cost Saving		●	●	●	●	●	●
Low Cost, QTAT Development	●	●					
Easy for Purchasing Products And Improve a Productivity at the Overseas Production Line				●		●	
System Confidential Affairs							●

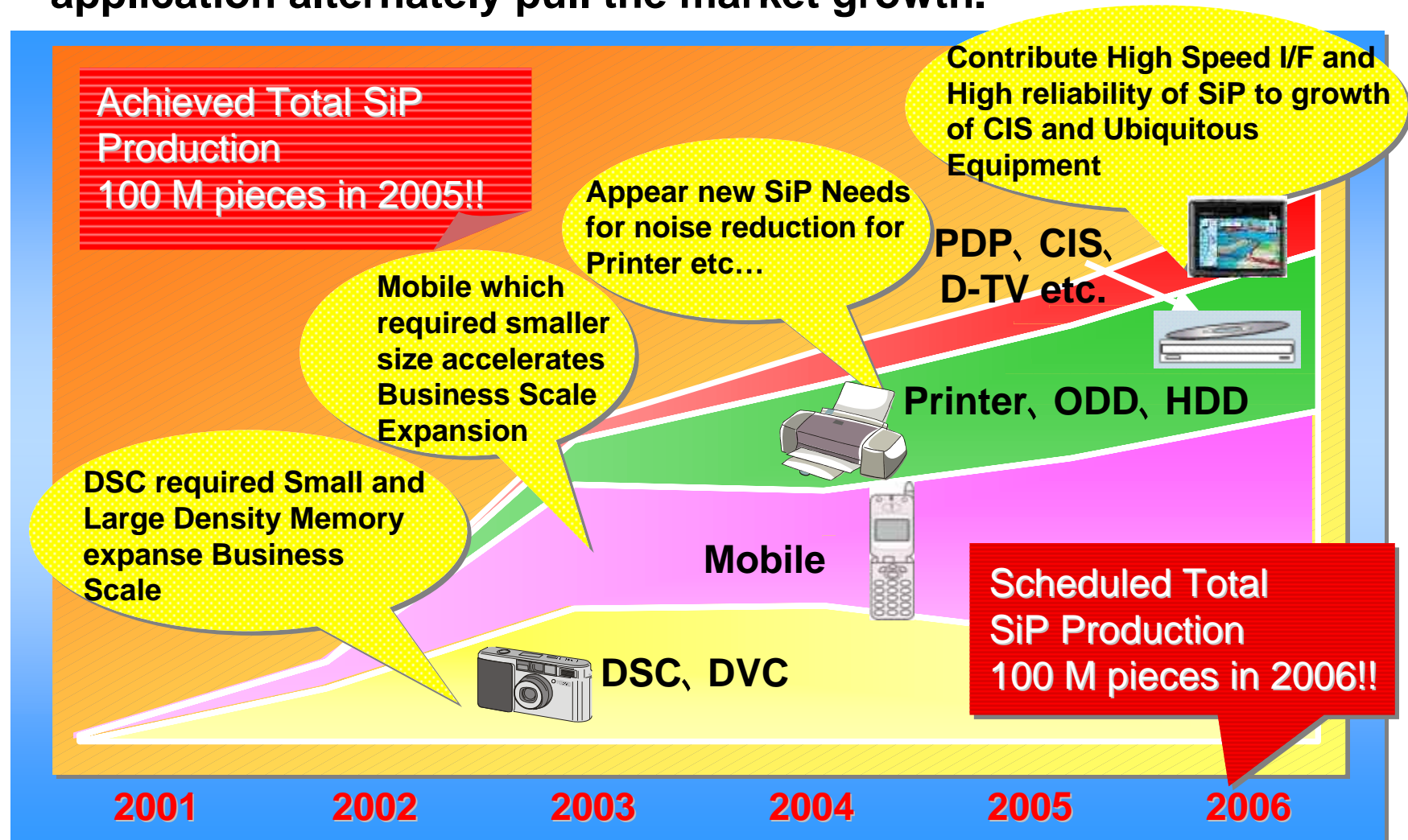
Advancing SiP Technology to realize Multi Function and High Powered



* KGD-Known Good Die

Renesas Leading SiP Market

- Making to high performance and the SiP technology of the application alternately pull the market growth.



Renesas SiP Production Quantity

5. Renesas SiP Consistent Design System

SiP Consistent Design System

- **SiP Test Design**

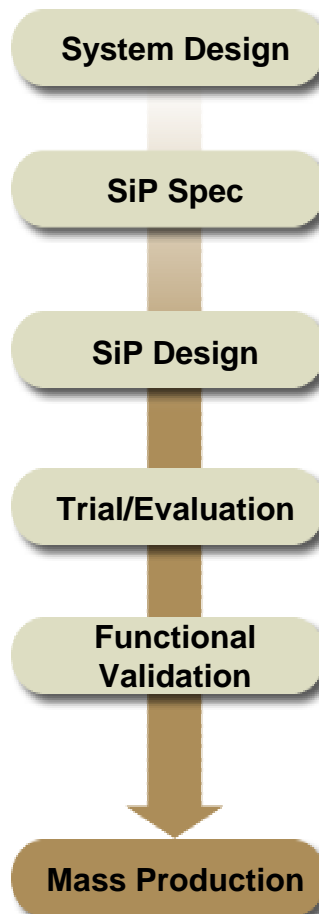
SiP Test Pattern

- **SiP Substrate Design**

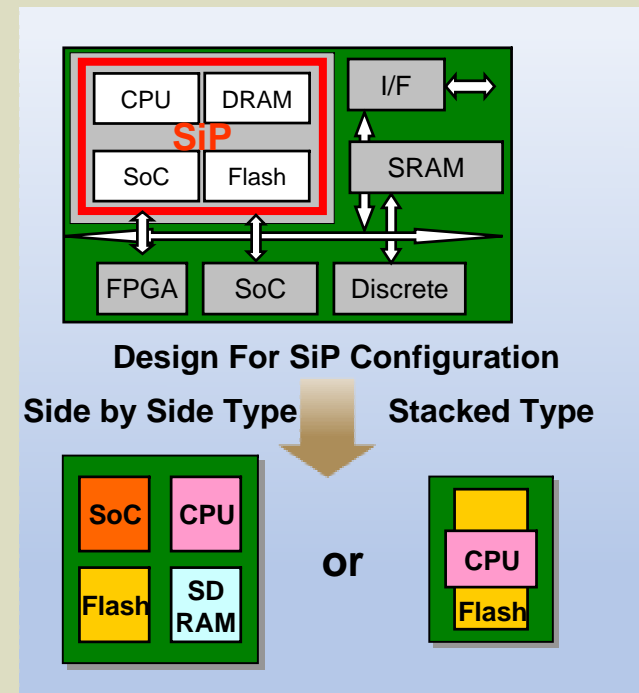
- (1) Reflection, Cross Talk Simultaneous Switching Noise
- (2) Thermal Register
- (3) High-frequency Substrate Design

- **SiP Functional Validation**

- (1) SiP Characteristics
- (2) Production Reliability etc.



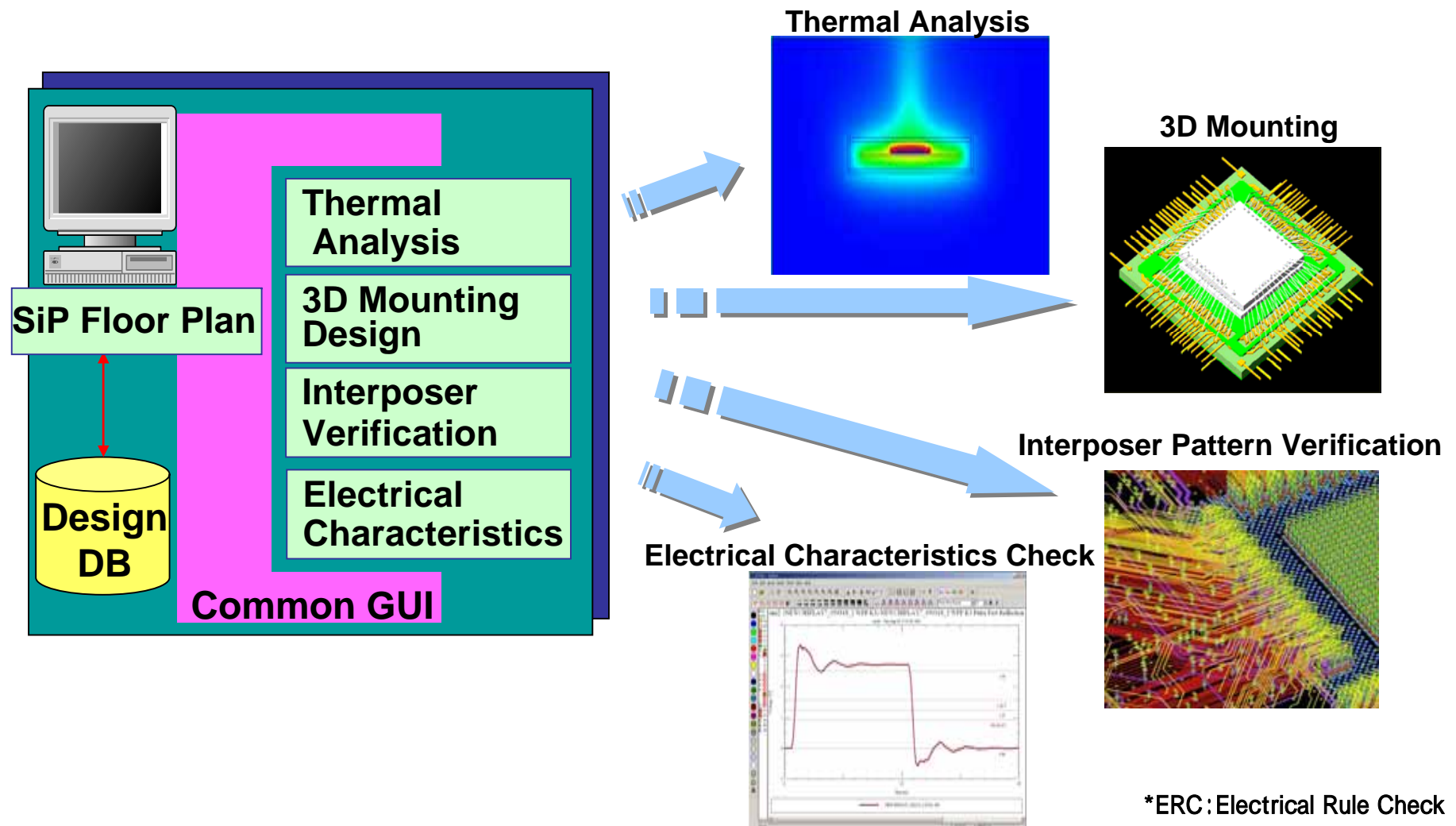
Total Support from System Design to Test Design



SiP integration design environment

Design Quality Improvement

by Electrical Characteristics Check and Verification



SiP Floor Plan

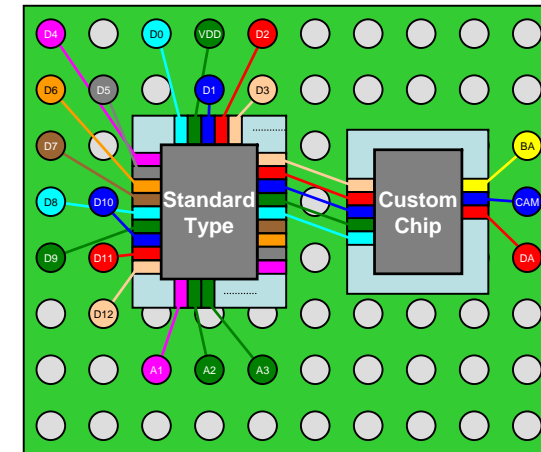
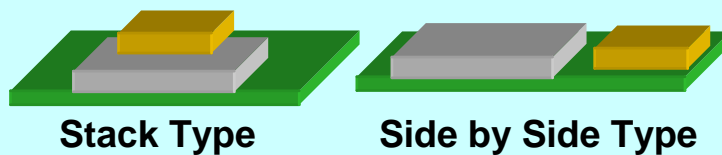
Our Goal:

SiP Design Which Fulfills the Performance, Power, Cost, PKG Size and Pin Numbers

• SiP Floor Plan

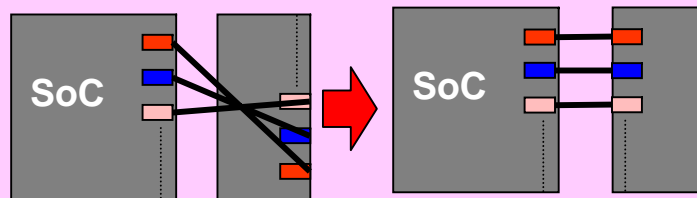
1. Decision on Mounting Type
(Stack Type or Side by Side Type)
2. Decision on Chip Alignment
with Considerations of Simple Substrate Pattern

Chip Alignment Inspection

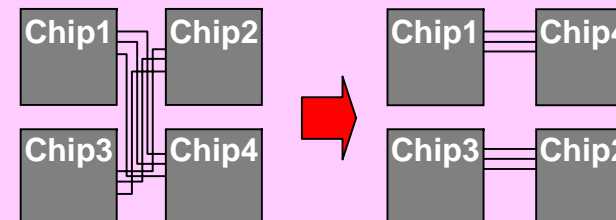


SiP Floor Plan Result

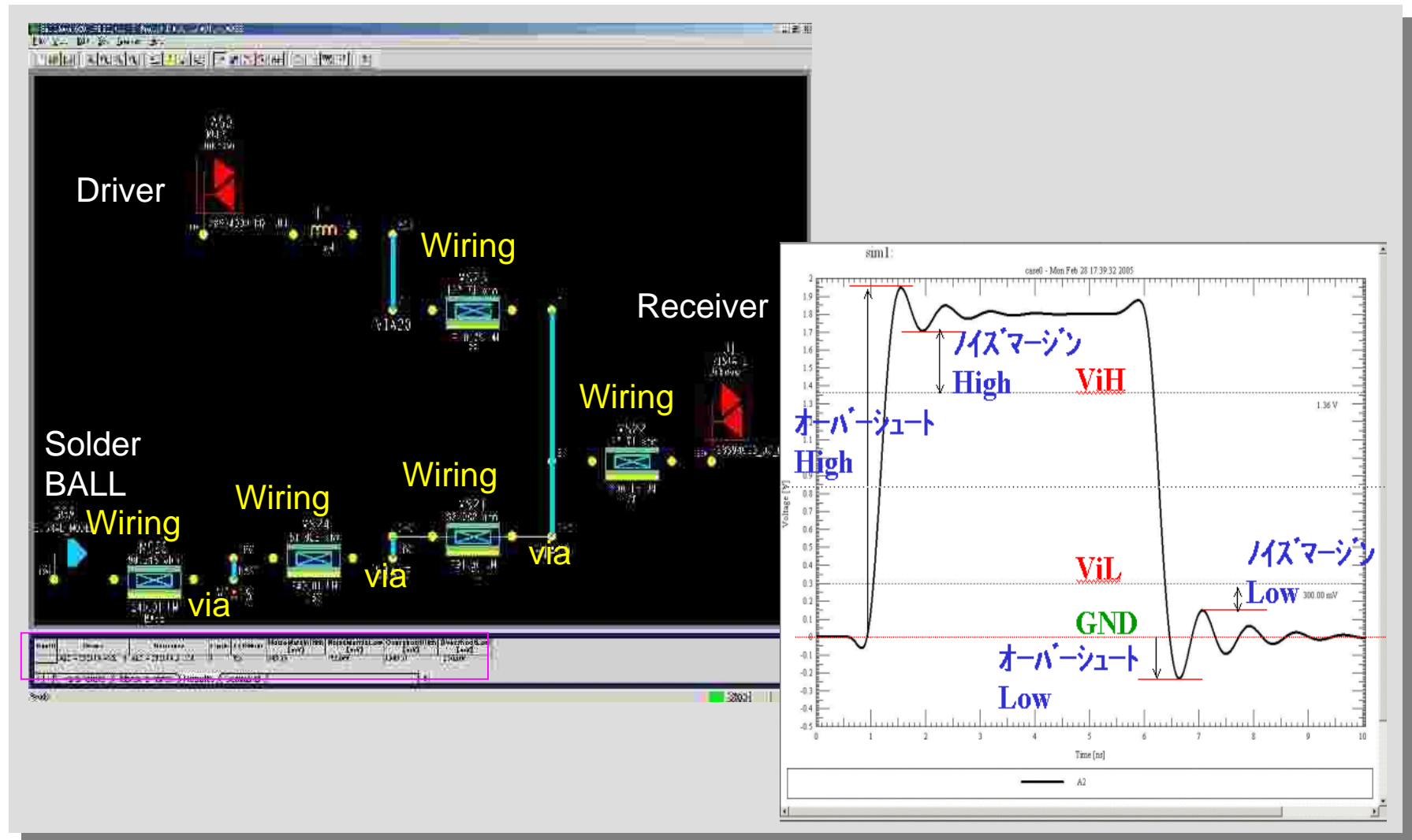
Examination of Simple Substrate Pattern (1)



Examination of Simple Substrate Pattern (2)



Example of chip interconnection SI analysis result



IR-drop Analysis Enhancing Technique

Examination for SiP

■ Achievement means

Making Macro Model From Non-Attention Chip
(RLCG+Equivalent circuit by current)

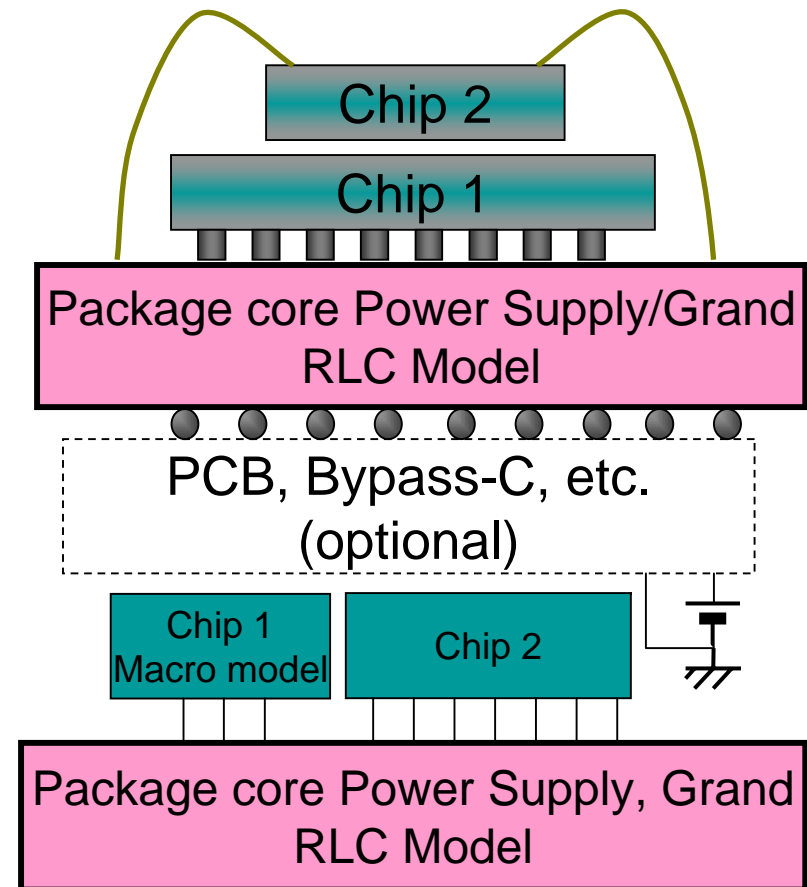
■ Action Item

Chip Power Supply · Means of Making
GND of Macro Model
Chip Power Supply · Analyzing Means of including
GND of Macro Model

■ Effect

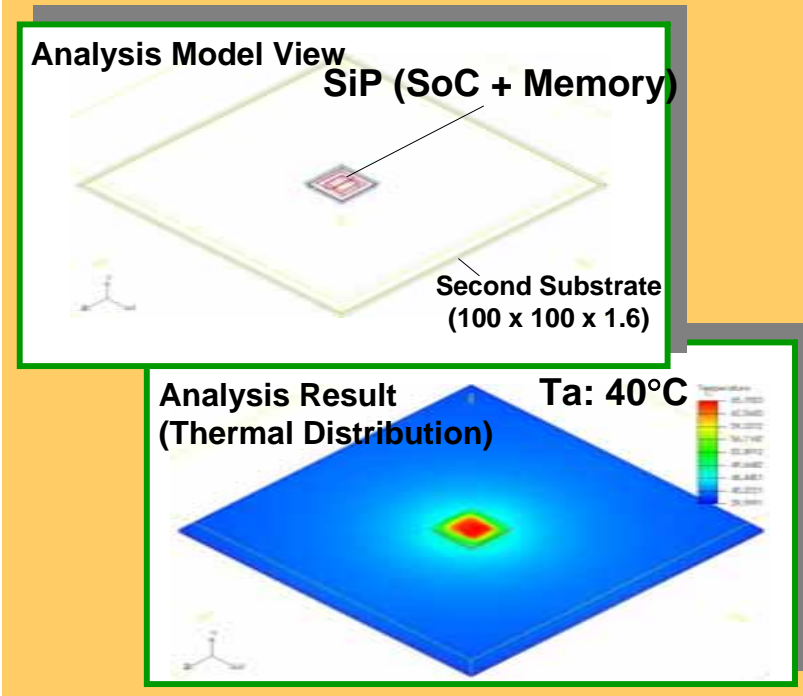
Grasp achievement of chip interconnection noise
spread for which Interposer is used

Reduction in power supply
and number of GND balls in SiP PKG

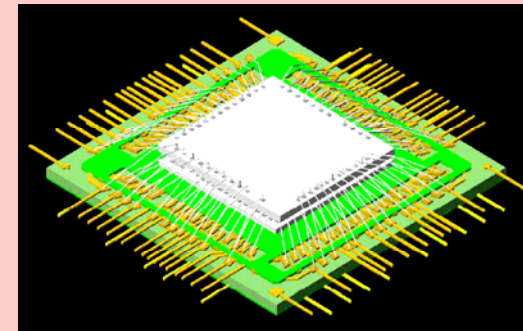


SiP Simulation Cases

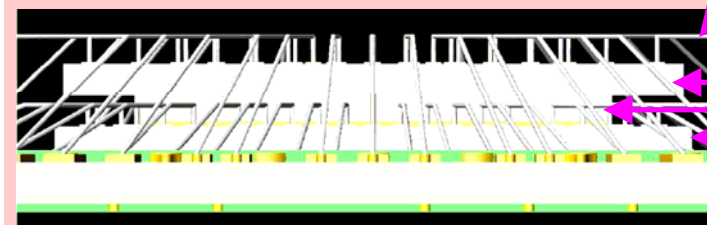
• Thermal Analysis Simulation



• 3D Wire Bonding Design and Verification



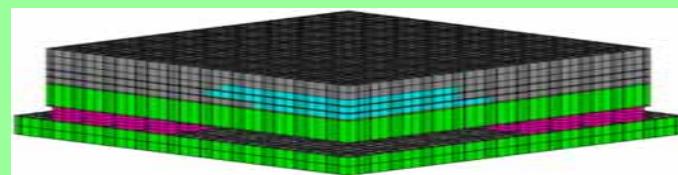
Verification Wire Clearance by 3D Model



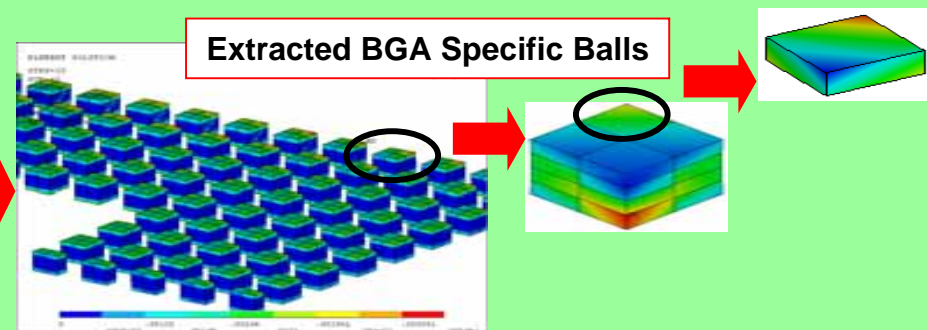
Wire

Upper Chip
Spacer
Under Chip
Board

• Evaluation of SiP Stress Simulation



SiP Simulation Model

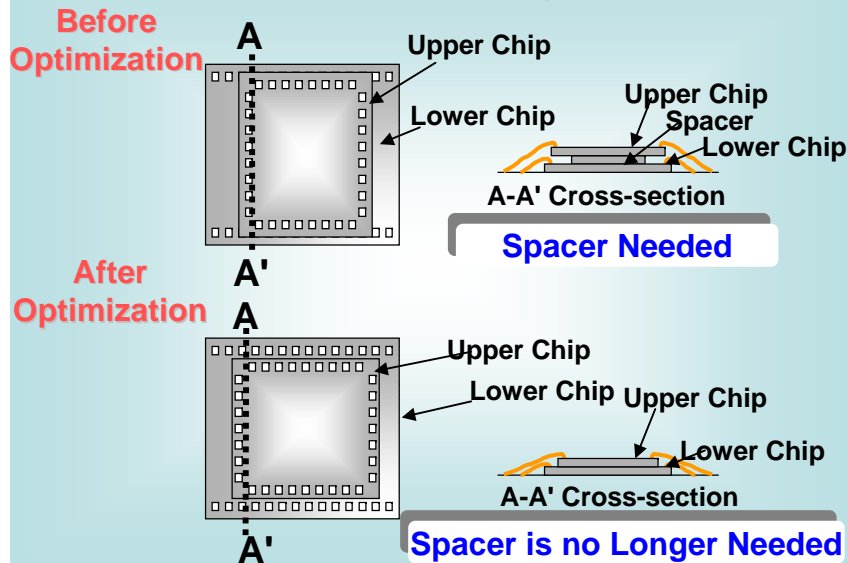


6. Design for SiP

SoC design to consider SiP (Design For SiP)

- Realize Suitable SiP Structure \Rightarrow Consideration cost for SiP Design Technology -

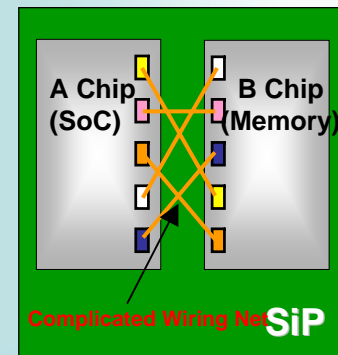
[1] Optimization of Chip Configuration



[2] Optimization of I/O Pad Arrangement

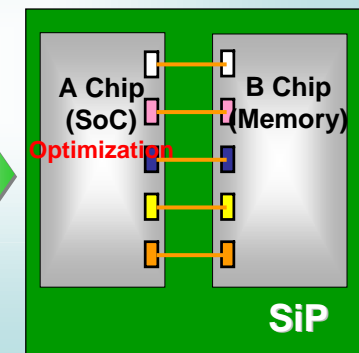
Before Optimization

Many SiP Substrate Layers
More Layers, Must use B/U Substrate



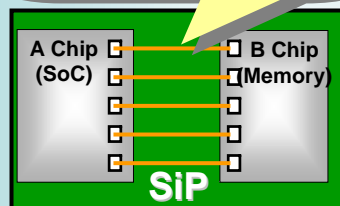
After Optimization

Less SiP Substrate Layers
4 or Less Layers,
Able to use Glass Epoxy



[3] Optimization of I/O Buffer Drivability

Wiring on the Substrate
Long/Short Wire
 \Rightarrow Less Parasitic Components



Increase Noise
Difficulty with SI Management

Effect

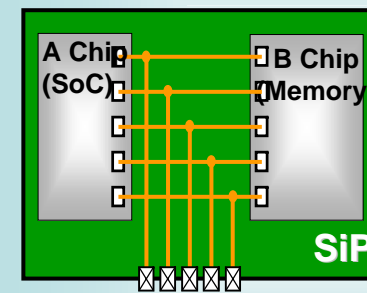
- Lower I/O Electric Power
- Reduce Simultaneous Switching Noise

Better SI Management by Optimizing
Buffer Drivability



[4] Embedded Test Circuit Saves the Number of External Terminals

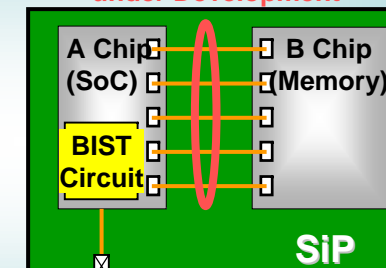
Conventional



Signal Terminals Used Only in SiP
(Ex. Memory Bus)

Output All signals

Embed a Test Circuit on Chips under Development



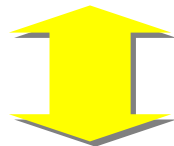
Output Test Results

Reduce External Terminals
Input Special BIST Circuit

Design for SiP

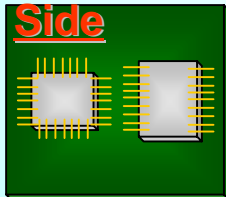
QFP Type SiP

Side by Side QFP Stack-QFP

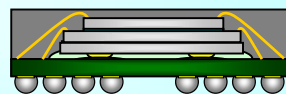


BGA Type SiP

Side by Side



Chip-Stack



<Advantage with SiP>

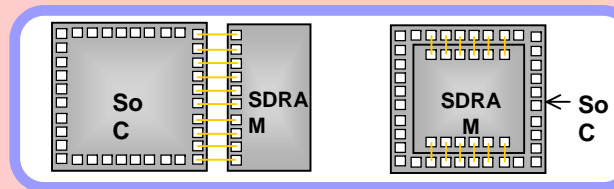
- Reduce design load by high-speed bus unnecessary design
- Reduce quantity of system board, size and substrate quantity
- Part arrangements simplification

<Advantage>

- Possible to reduce assembly cost for using standard lead frame

<Disadvantage>

- Required SoC design for embedded memory
- Limited Quantity of Embedded Chip (about 2chip)
- Low Wiring Flexibility

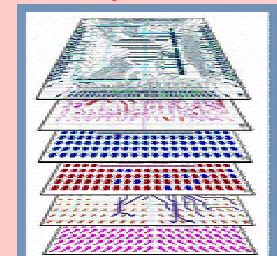


Need to adjust pad position perfectly

<Advantage>

- Possible to improve free wiring by multi-Substrate and electrical characteristics improvement
- Possible to optimize wiring high speed bus and power supply/GND wiring

Design of interposer optimized



<Disadvantage>

- Cost higher compared to QFP type

<Strategy of total SiP cost reduction>

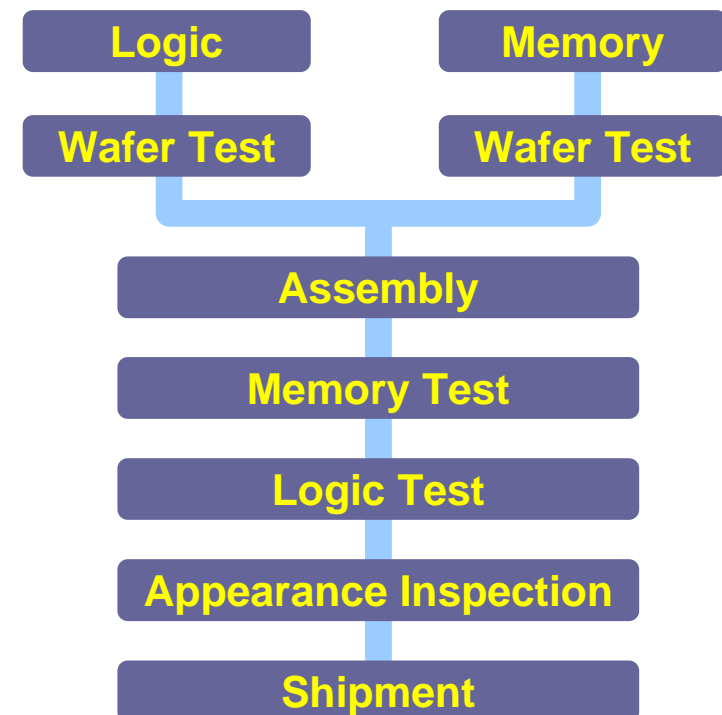
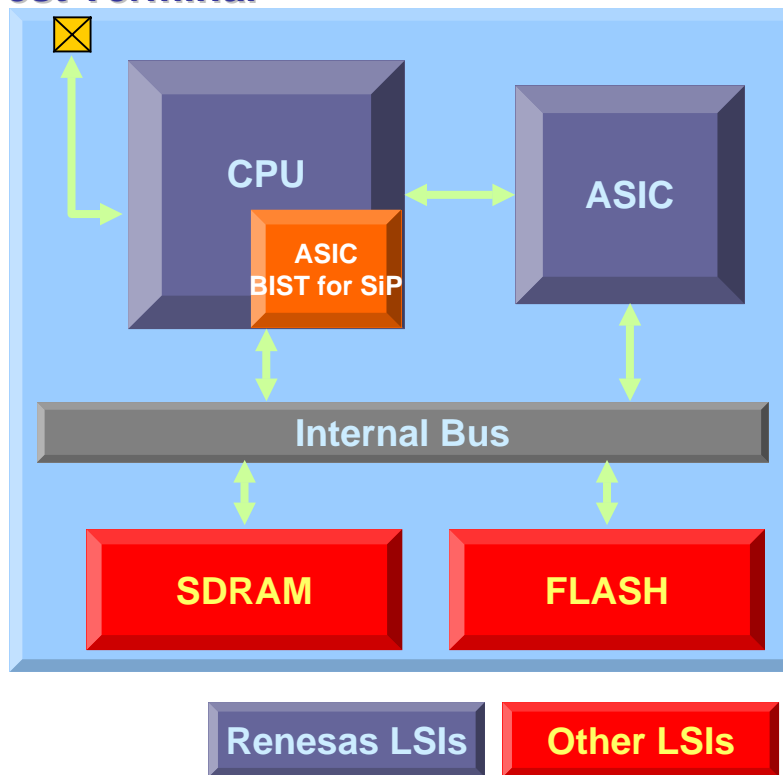
- Reduction of number of signal
=> Reduction of number of layers
- Reduction of external terminals by adopting test circuit test
- Customized SoC design for optimizing SiP structure

SiP Test Strategy

Quality Guaranteed by RENESAS Original Testing Method

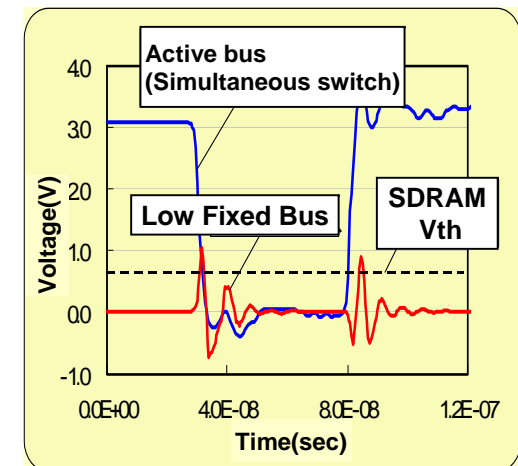
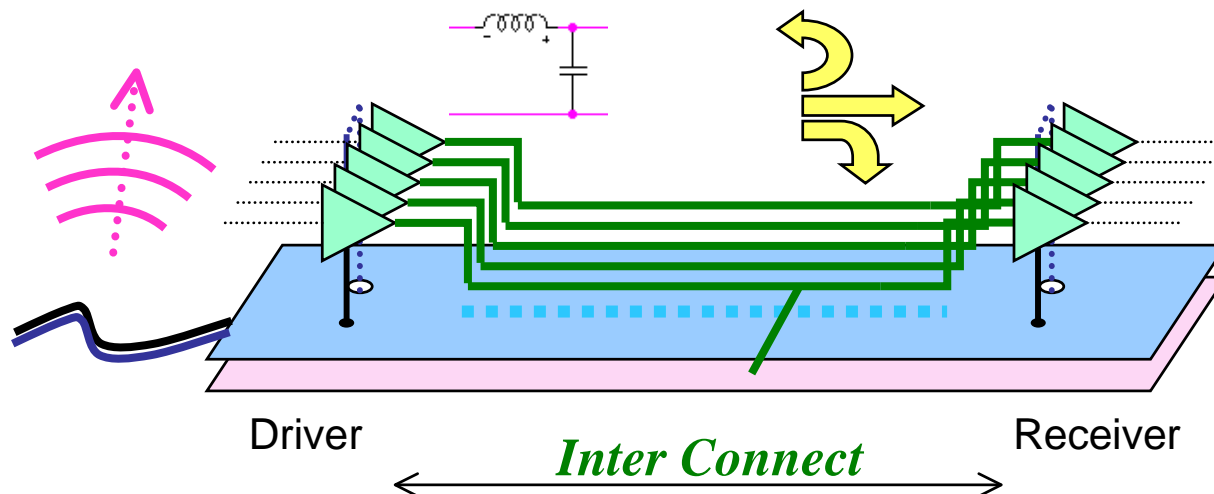
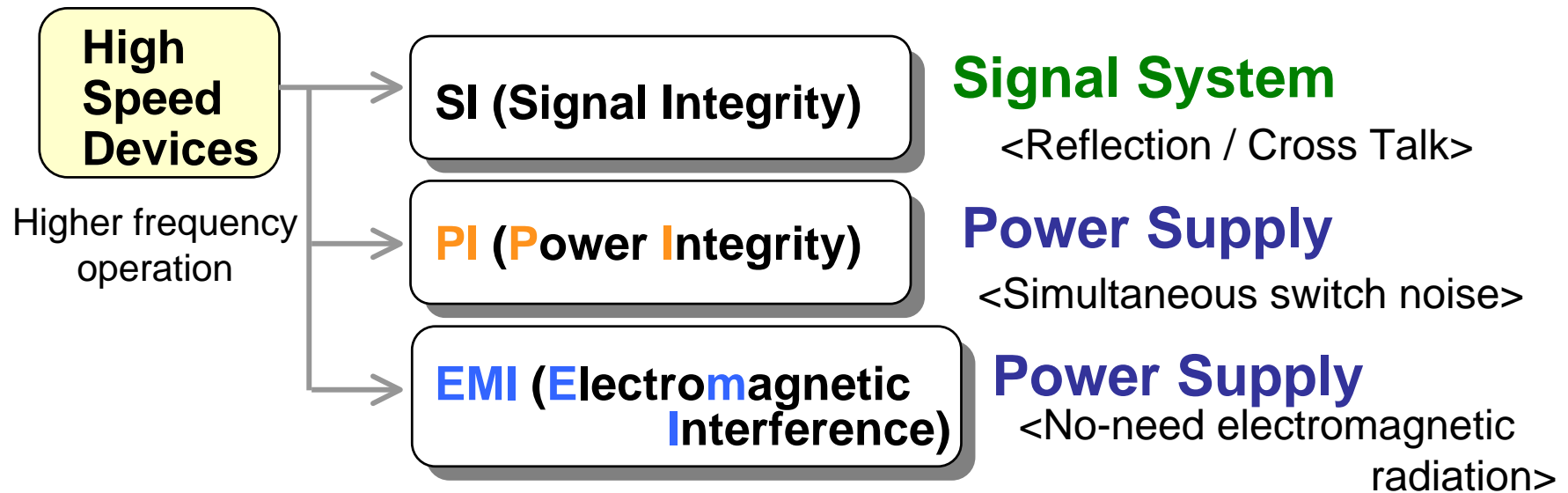
SiP System Test with Test Terminal

Test Terminal

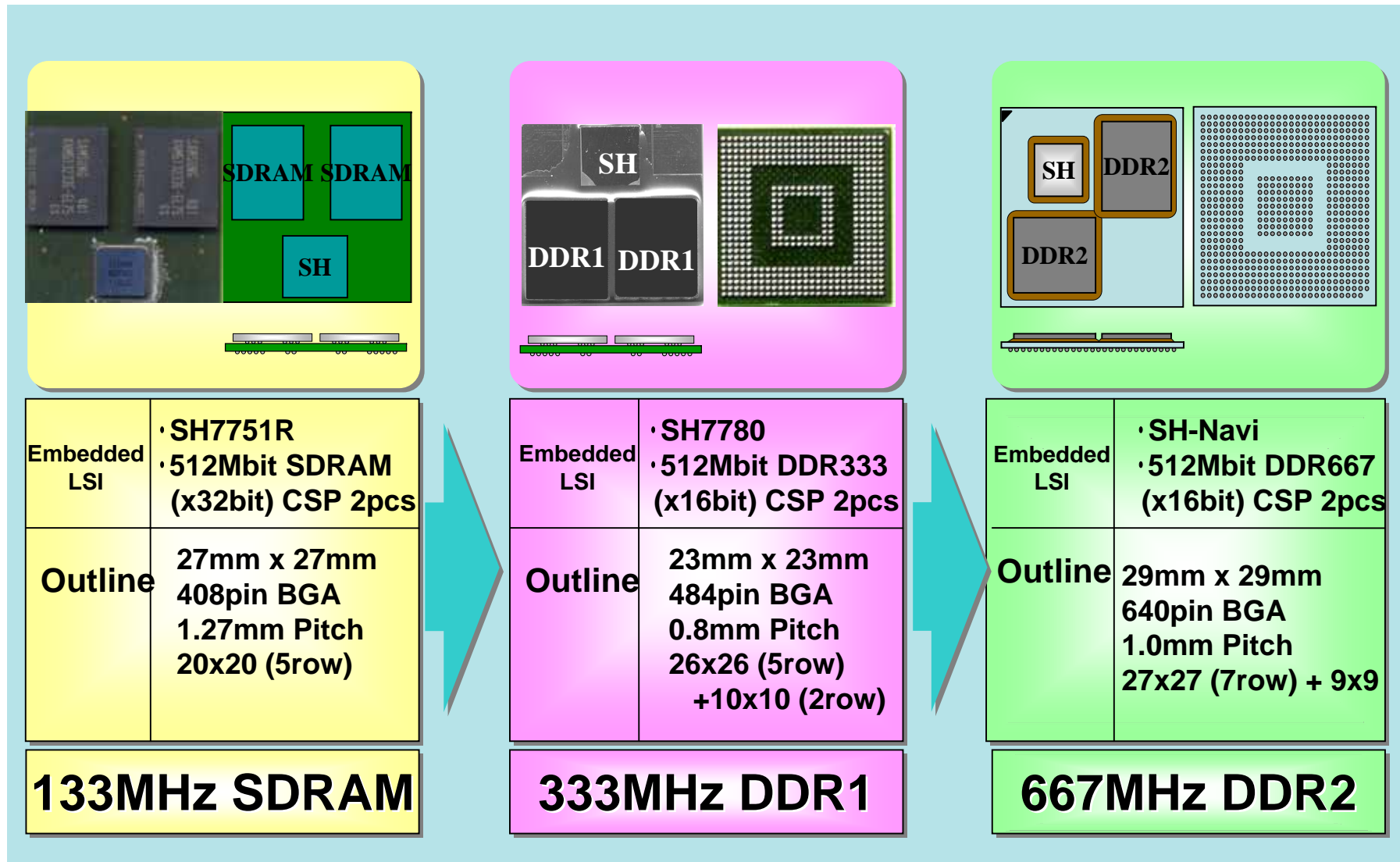


7. SiP Design Technology for High Speed I/F

Noise Problem of Speed-up and Mounting System

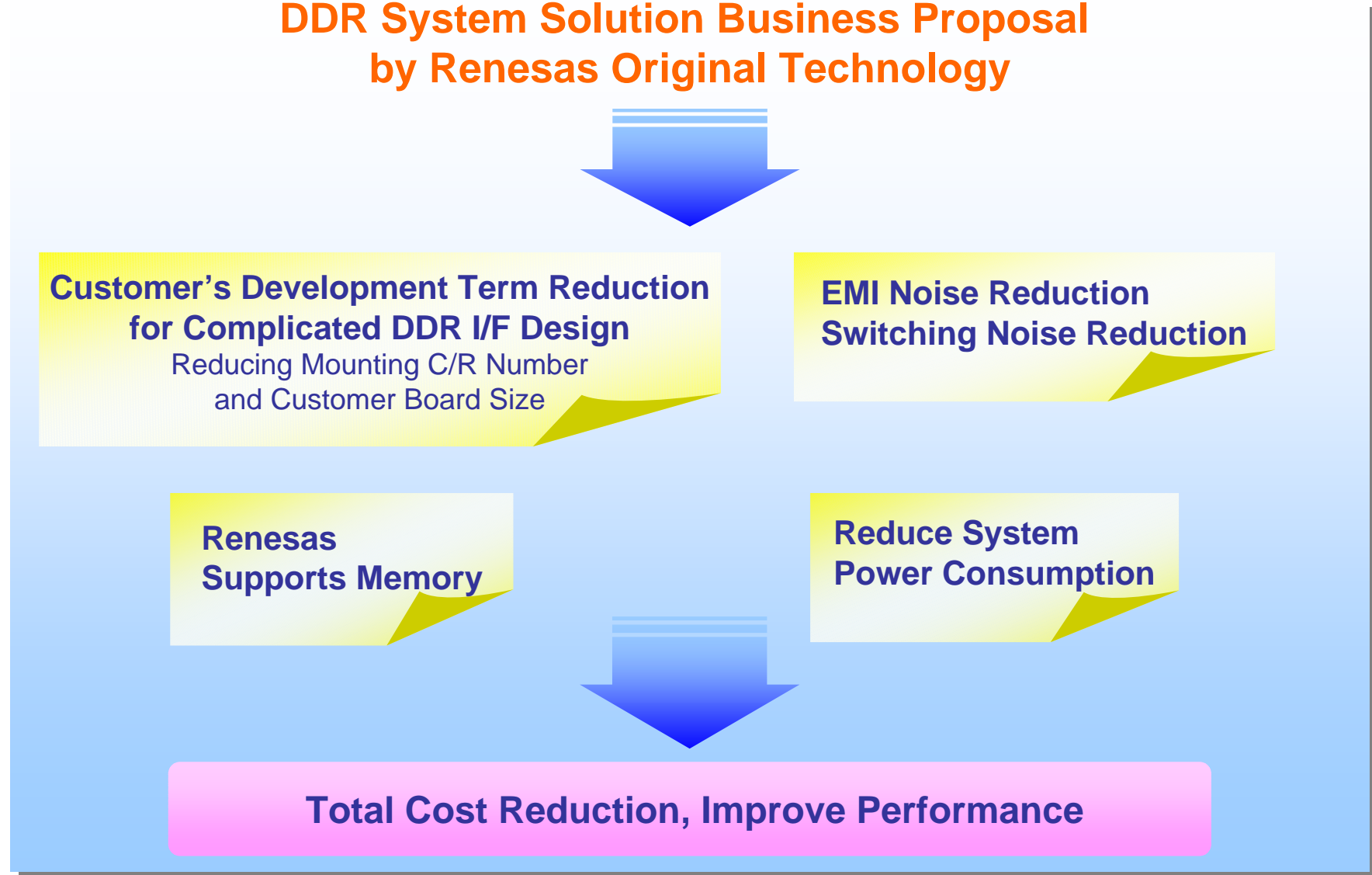


SiP Product Roadmap for High Speed



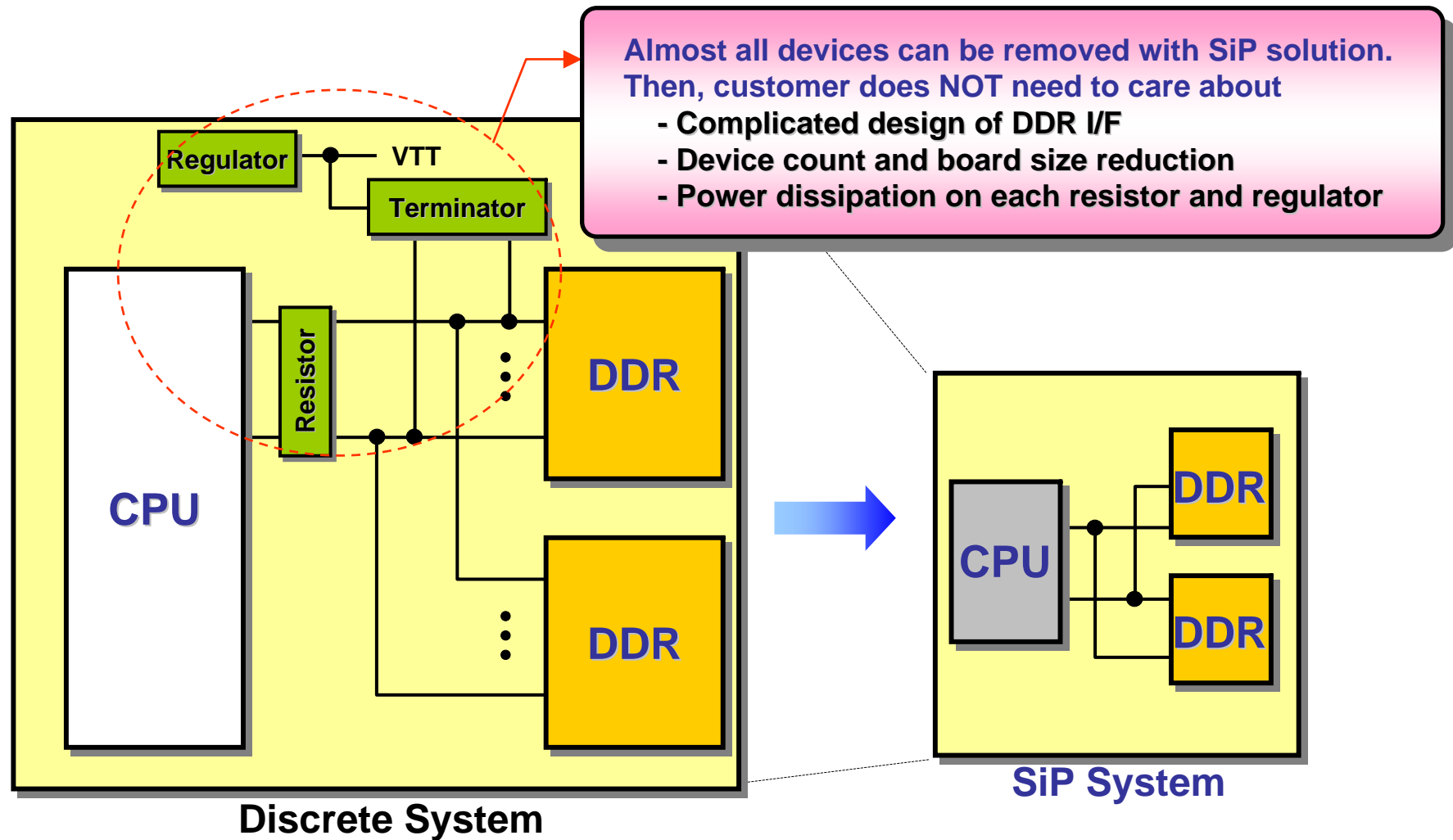
SiP Solution for High Frequency System

DDR System Solution Business Proposal by Renesas Original Technology

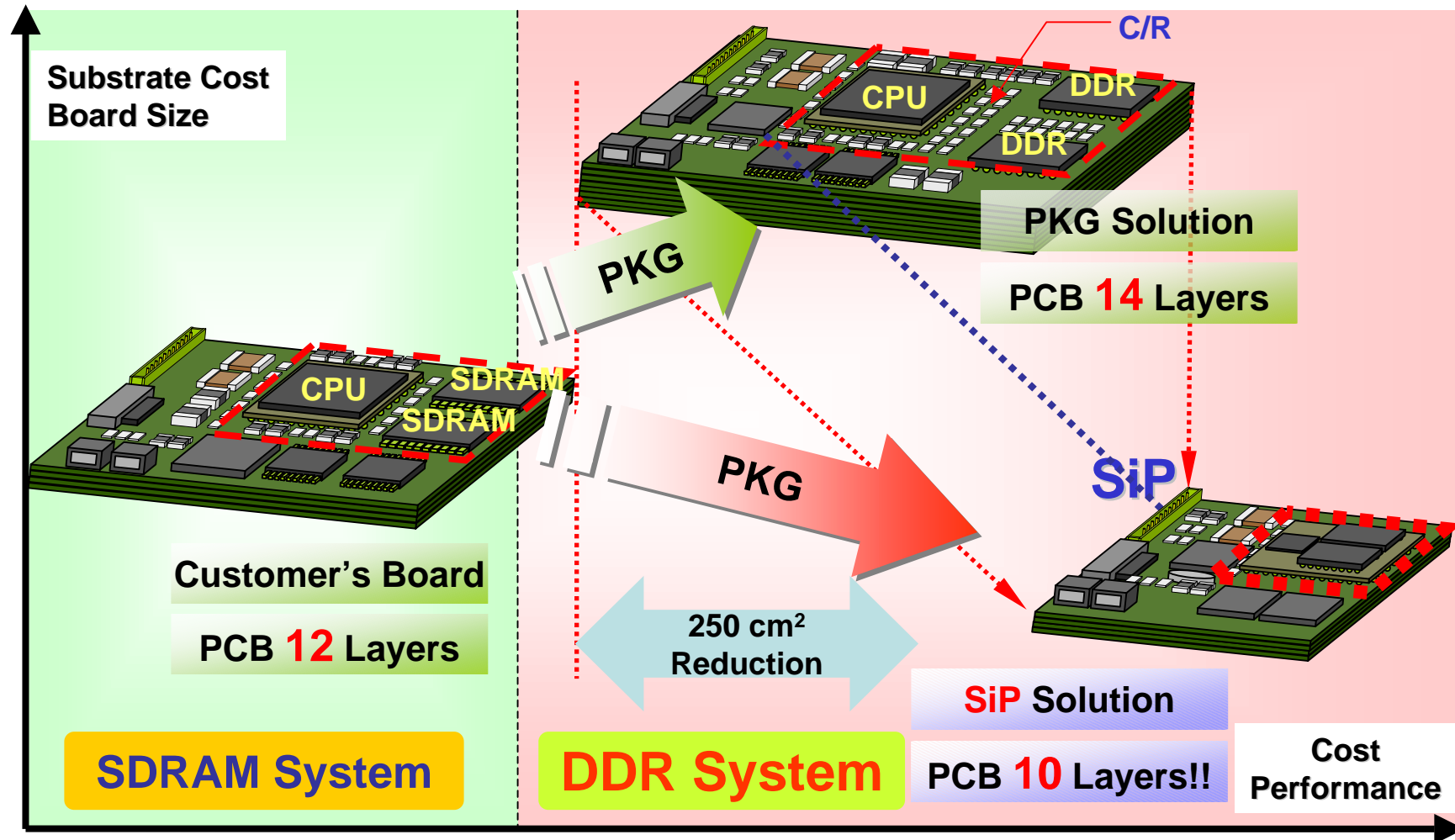


Easy DDR System Design by SiP

Renesas SiP makes customer free from the design of complicated DDR I/F



Total System Cost Advantage of SiP DDR



The strengths based on DDR-System

■ Reduction of Resistance of DDR IF Series and Terminate Resistance

- * The Optimization Design of SiP
Reduces series resistance and the terminator.
- * A high-speed design of DDR IF is unnecessary.

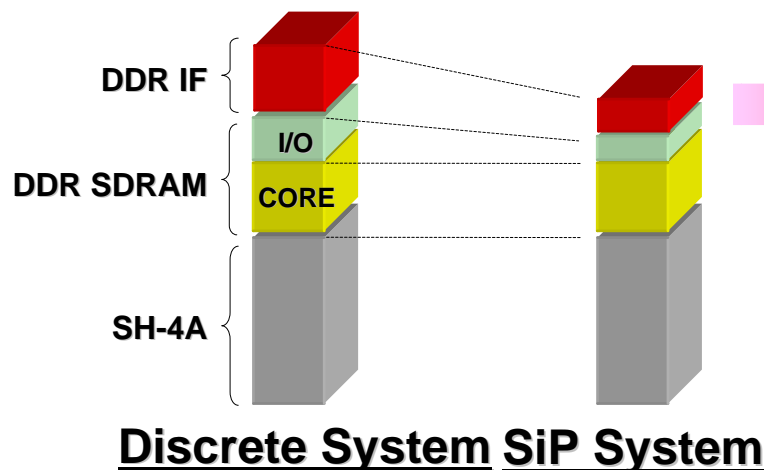
■ Effect of electric power decrease

- * The power consumption of DDR IF can be decreased.
- * Half the output electric power of DDR can be decreased by the drivability control.
- * The power consumption of the regulator of VTT can also be decreased.

Graphic · DTV Field



■ Power Comparison

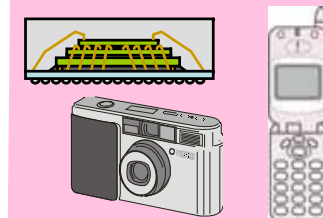


Reduce Power
Consumption of
DDR I/F Power

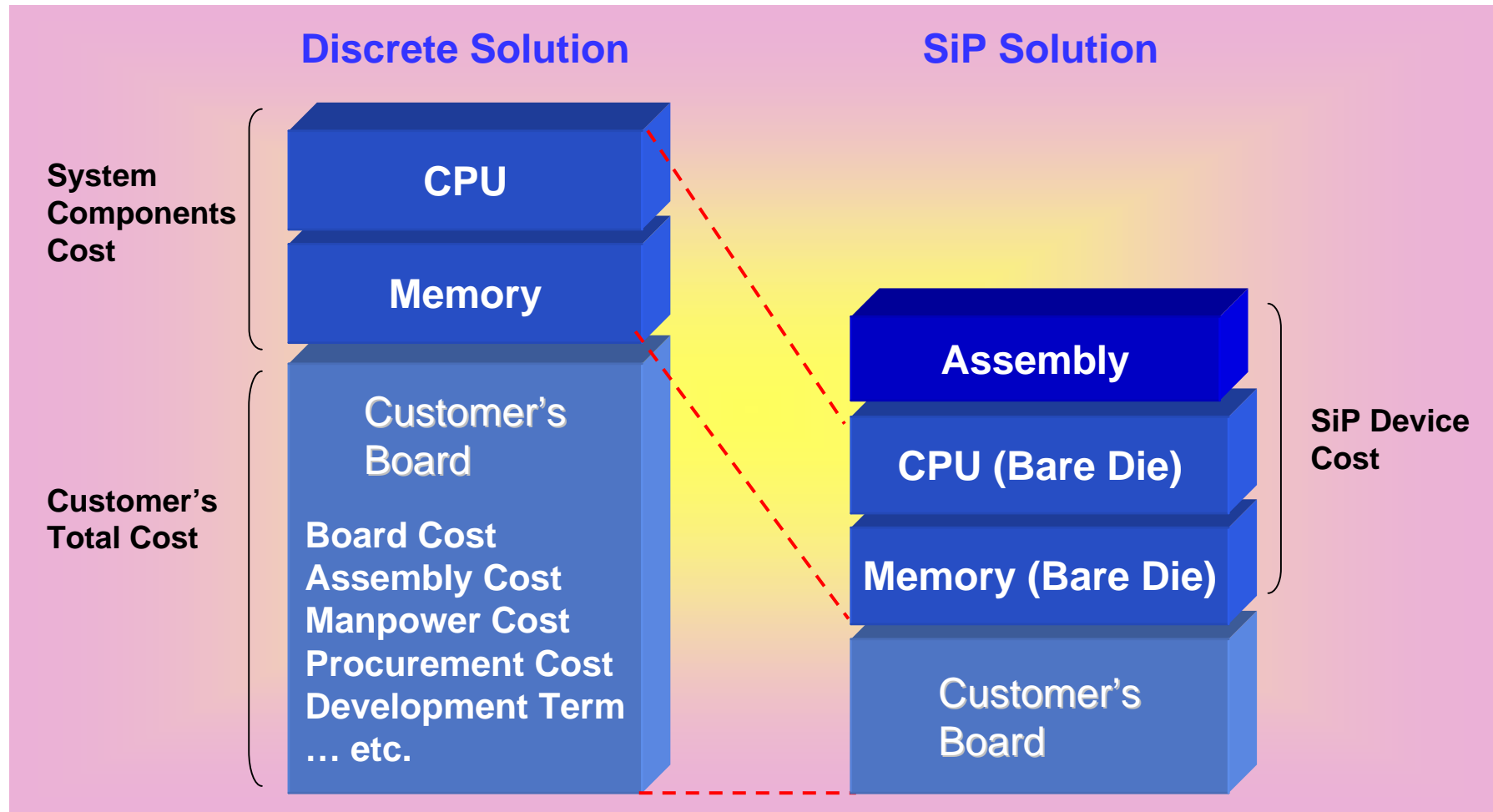
CIS Field



Celler · DSC Field

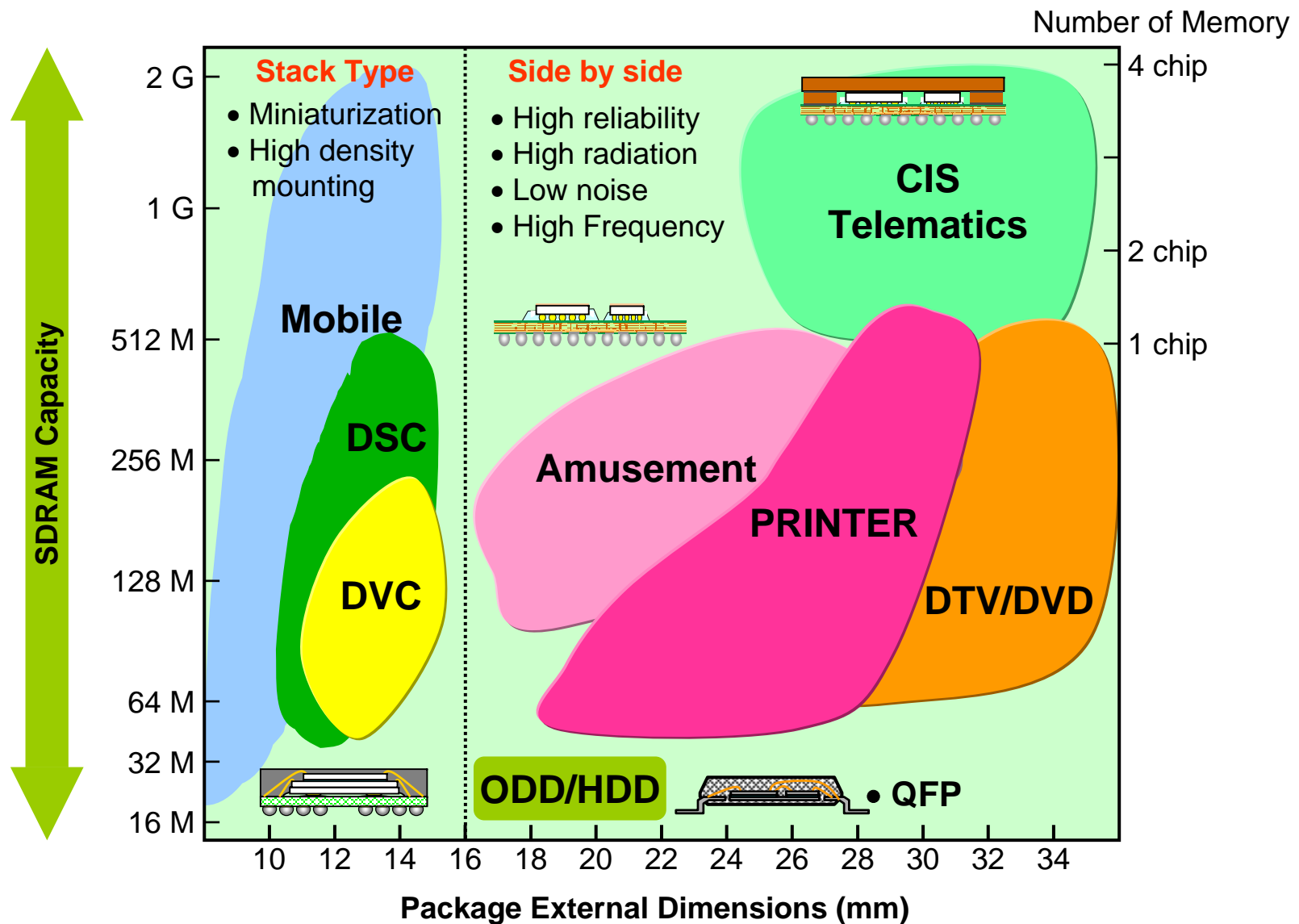


SiP can save Customer's Total System Cost



8. SiP Mounting Technology

Required Memory size by Application



Technology to realize miniaturize and high quality

- Applied the result of the top-level world research to the mounting technology.
- Support from design to mass production by mounting technology as the ITDM manufacturer

~ Realization of small size/high density SiP by FC technology + WB technology ~

Wafer super thin grinding technology

-300mm wafer super thin processing technology

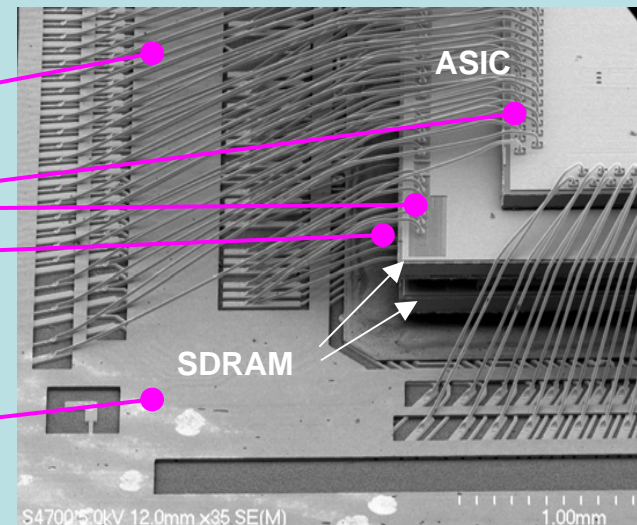
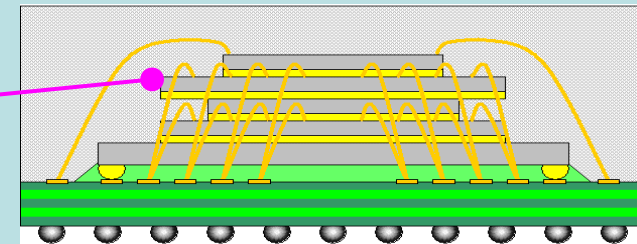
- 90 μm : mass production
- 50 ~ 70 μm : under development
- same processing level as 200mm wafer

Wire bonding connection

- Long wire formation
- Super low loop wire formation
- narrow pitch wire bonding tech.
- 50 μm pitch under mass production

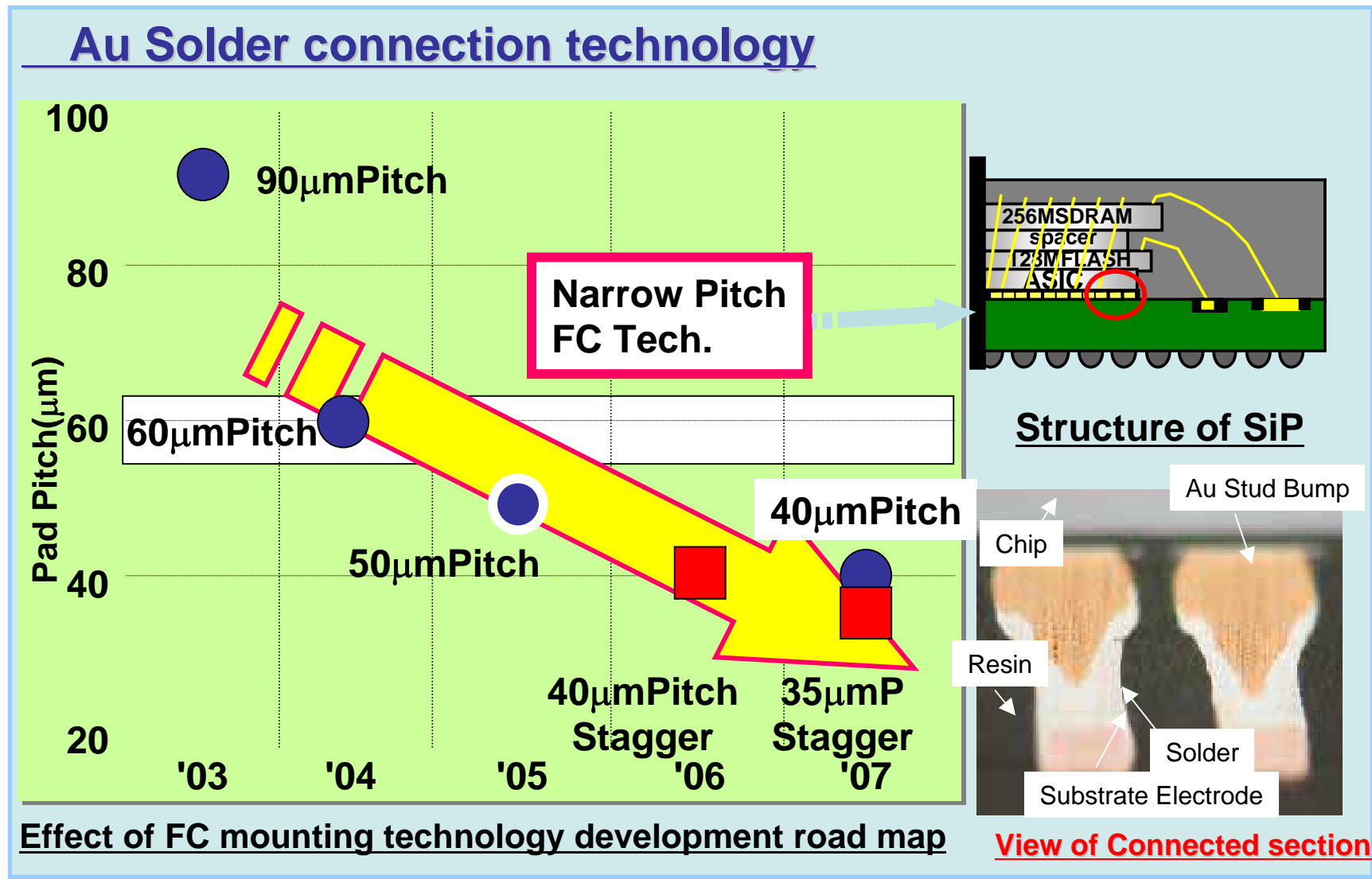
Board Technique

- thin board technique, low warpage substrate technology



5 layer solution for DSC

The Trend of FC (flip chip) Technology

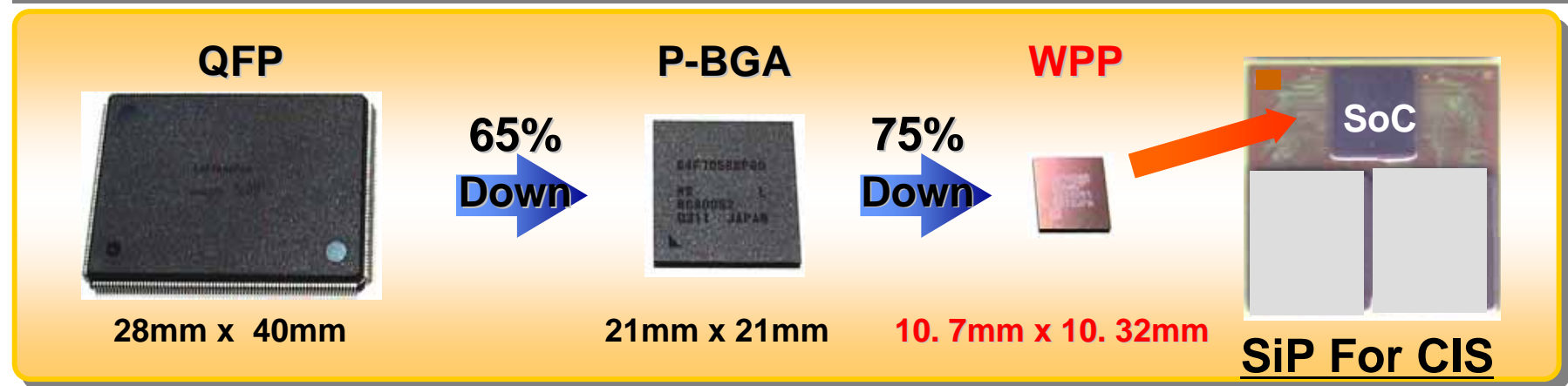
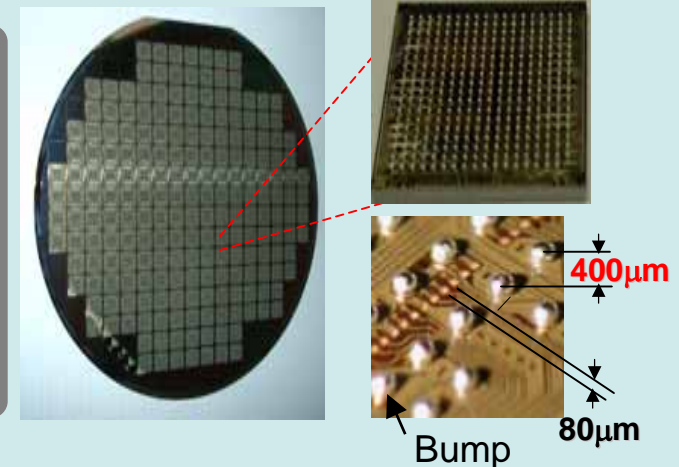


Renesas SiP Highly Reliable Flip-Chip Connection Technology

~ RENESAS Original Highly Reliable Technology by WPP Technology ~

WPP (Wafer Process Package) Technology

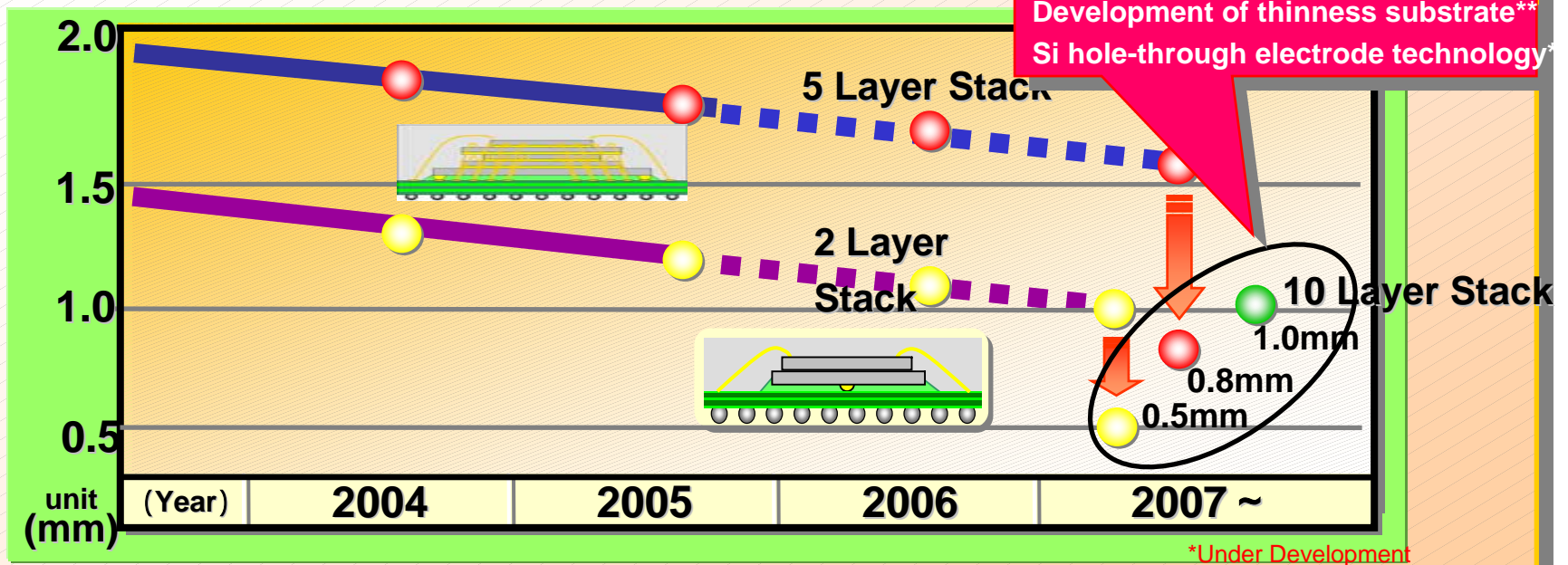
- Realized Real Chip Size Package
- Reduced Resistance · Inductance,
the best for **High-Speed Device**
- Improvement of **Connected Reliability**
with soldered joint
- Executed Test/Burn In to each chip,
and make possible **The High Reliability Guarantee**



Super Thin Stack SiP Trend

Trend of Package Height

~ For Large Capacity, High-Density Mounting ~

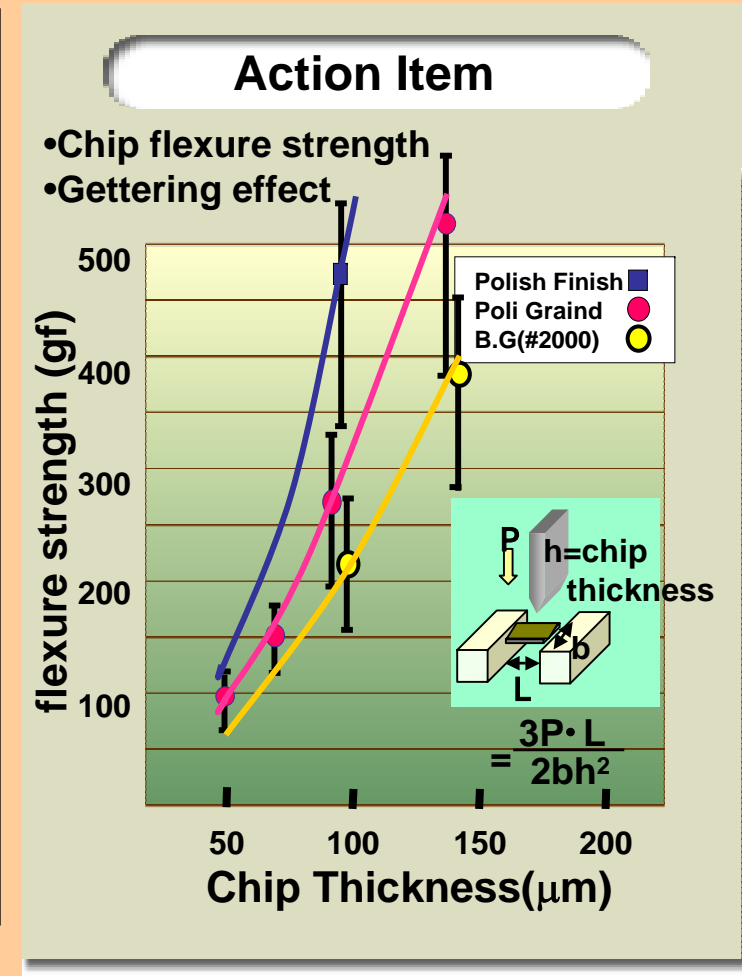
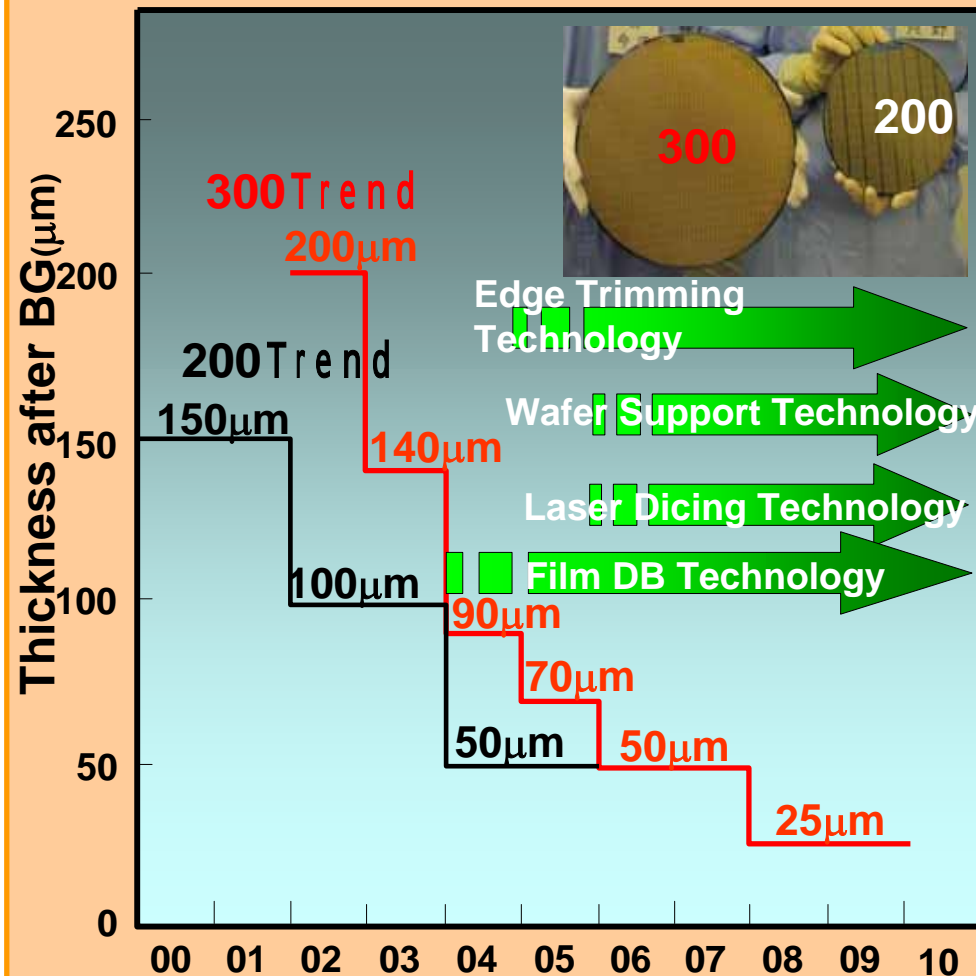


Required Technology Development

300 wafer ultra thin processing technology, thin substrate technology, and super-low loop wire bonding technology, narrow pitch FC die-attach technology

BG(Back Grind) Processing Technology and DB Technology Development Road map

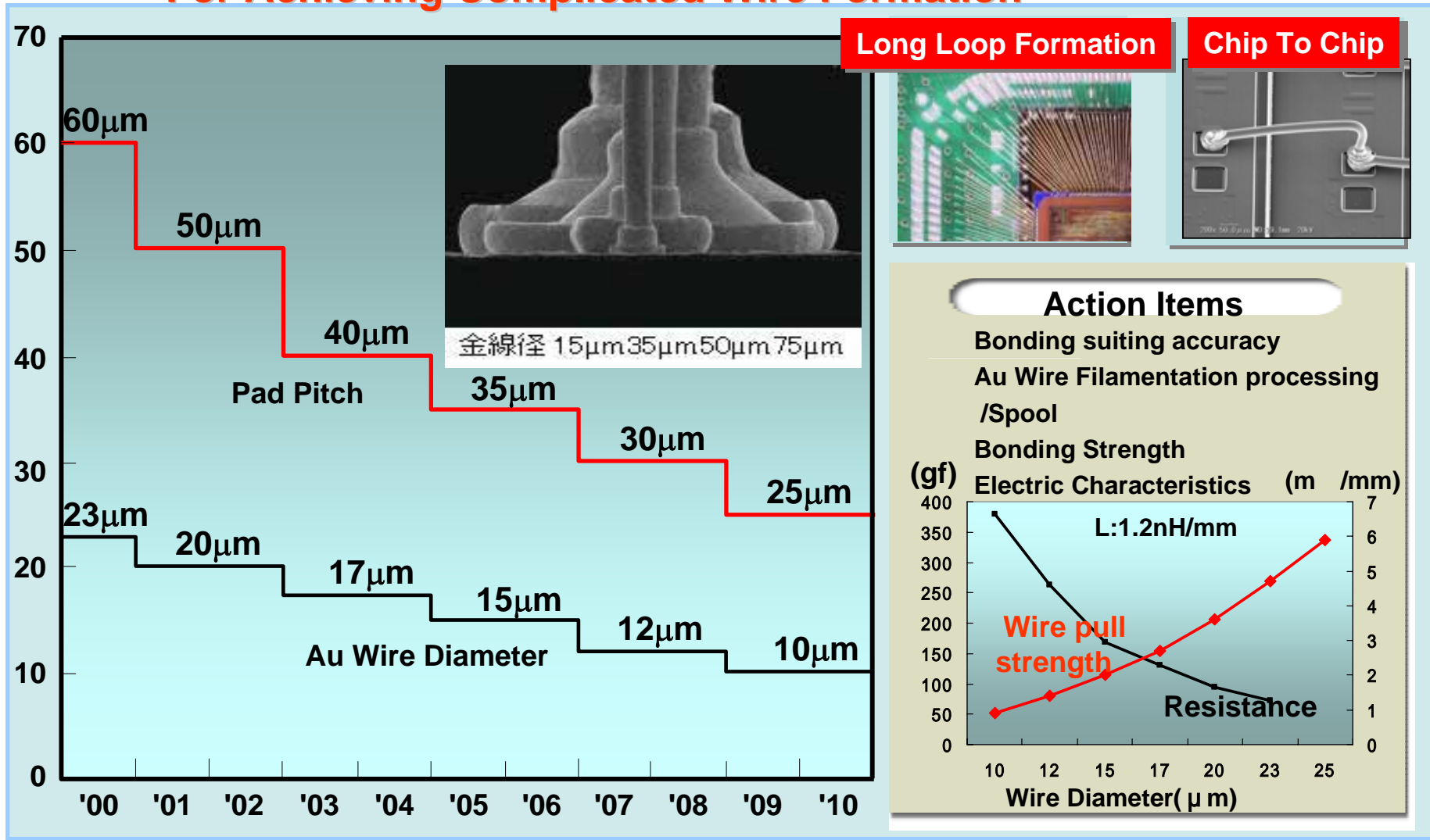
~ To Realize high density multiple memories, miniaturization ~



Road Map of Wire Bonding Technology

Development

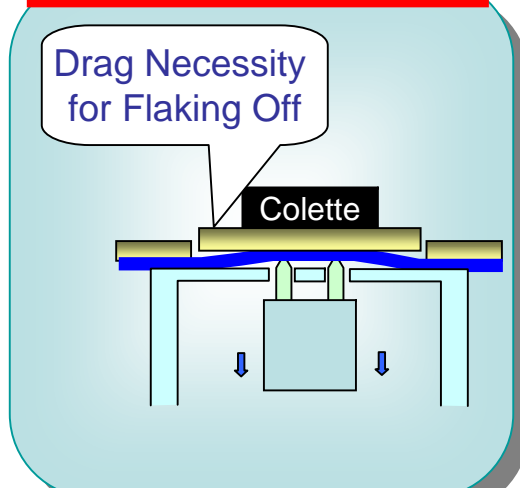
~ For Achieving Complicated Wire Formation ~



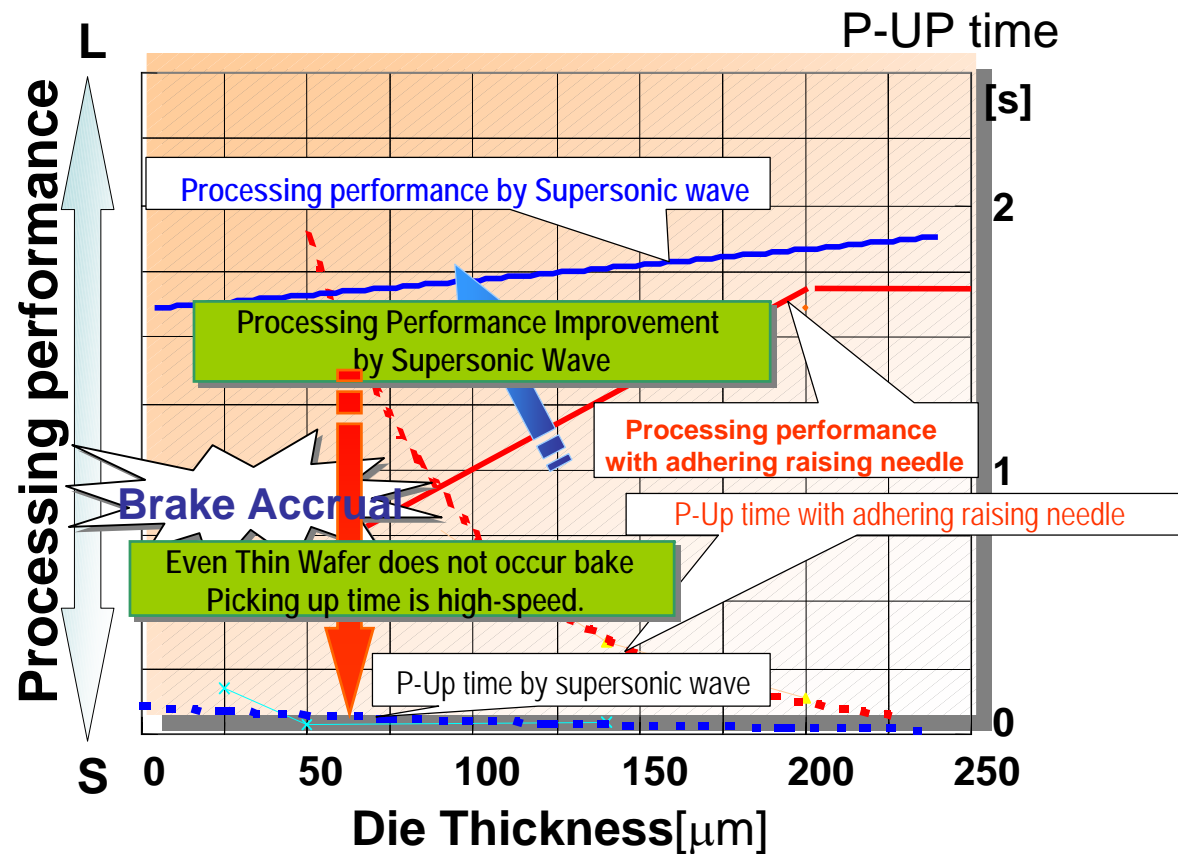
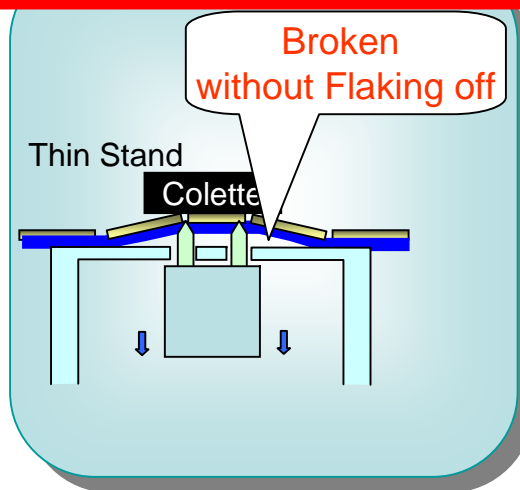
Thin Wafer Pick-Up Technology

~ Examination of picking up technology with supersonic wave ~

Before Optimization



Chip Thickness t 50 μm

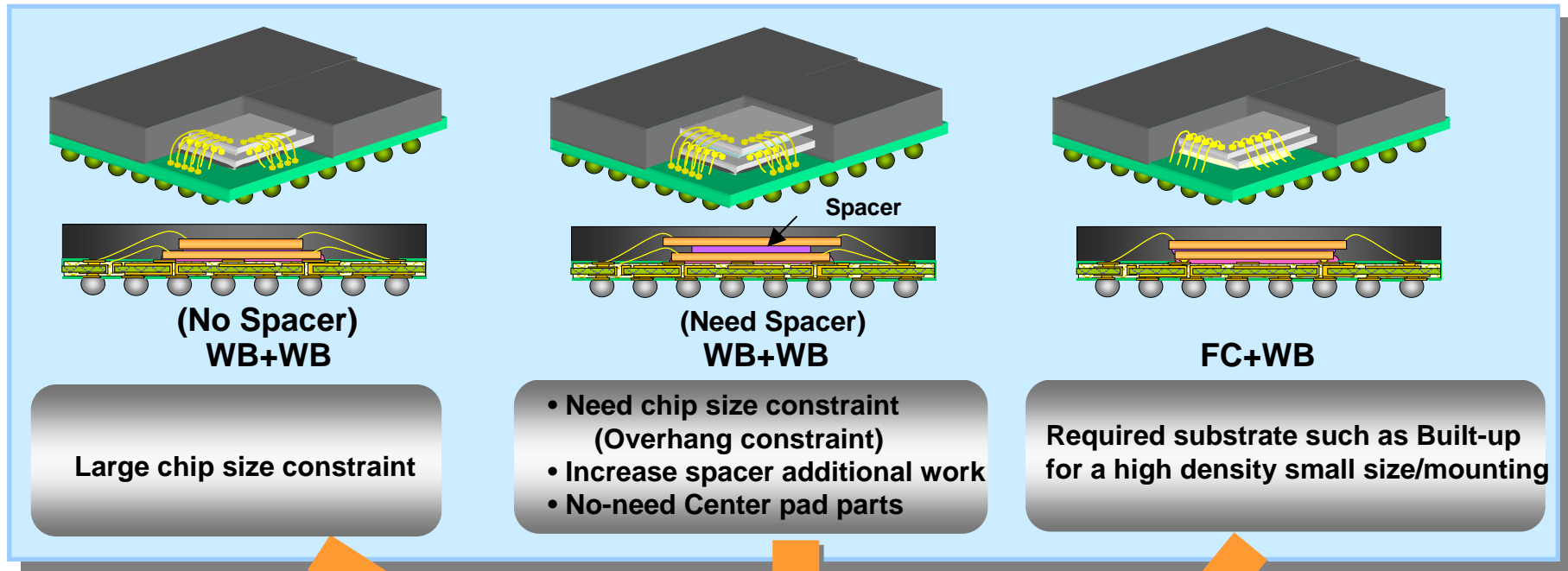


[Benefit of Supersonic Wave]

Even Thin Chip can be effective to produce
Good for Super-thin type Stack technology

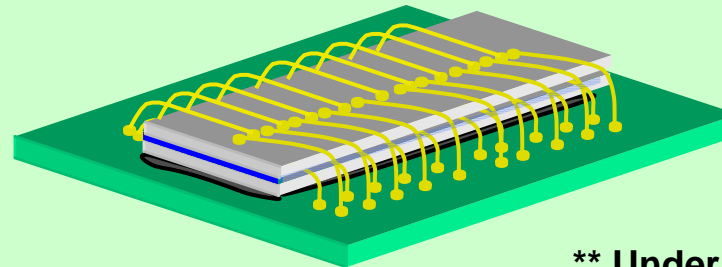
9. Stack SiP Development Trend

Spacer less Technology**



Decrease Mounting Constraint and Multi Stack Technology by increased Stack LSI

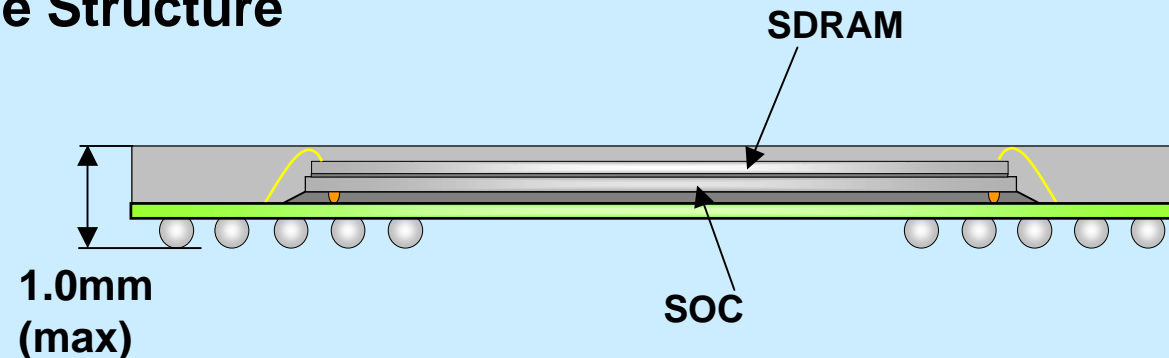
Spacer less technology



**** Under Development**

Thin SiP substrate**

■ Sample Structure



**Coreless substrate: Thickness less than 0.1~0.2mm
(Current Products 0.4mm)**



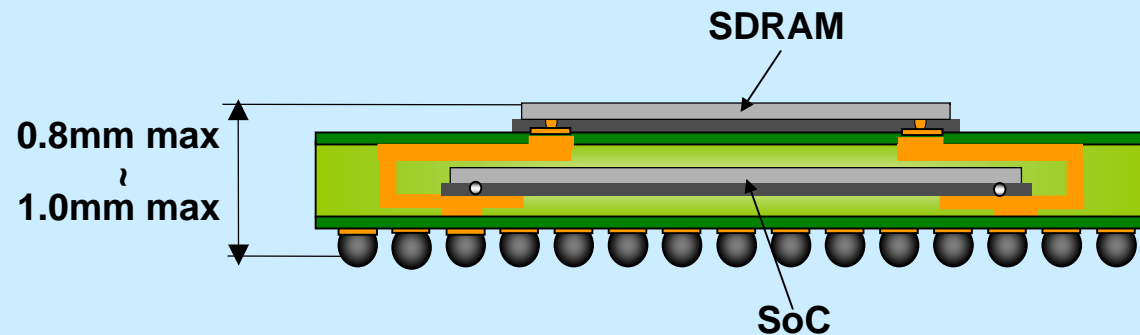
** Under Development

■ Advantage

- Suitable for thin/small products such as mobile or HDD/ODD

LSI embedded substrate SiP**

■ Sample Structure



Realize thin type by embedded SoC in the substrate
and FC connected SDRAM

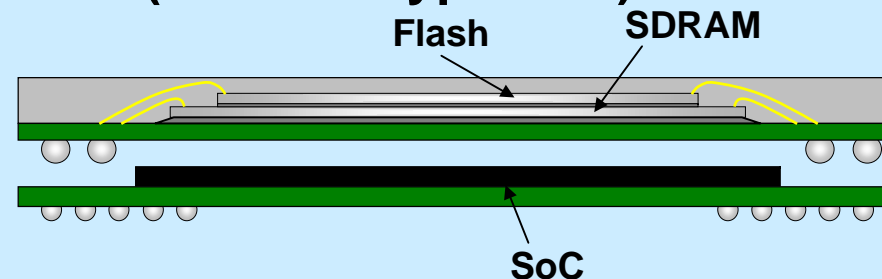
** Under Development

■ Advantage

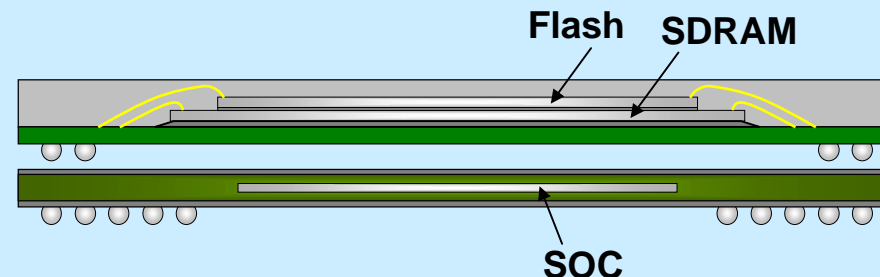
- Available for system black box such as security field
- Possible to make high density memory

PoP(Package on Package) Technology**

■ Sample Structure (mold/FC type PoP)



■ Sample Structure (substrate LSI buried type PoP)



Using LSI embedded technology for lower substrate

** Under Development

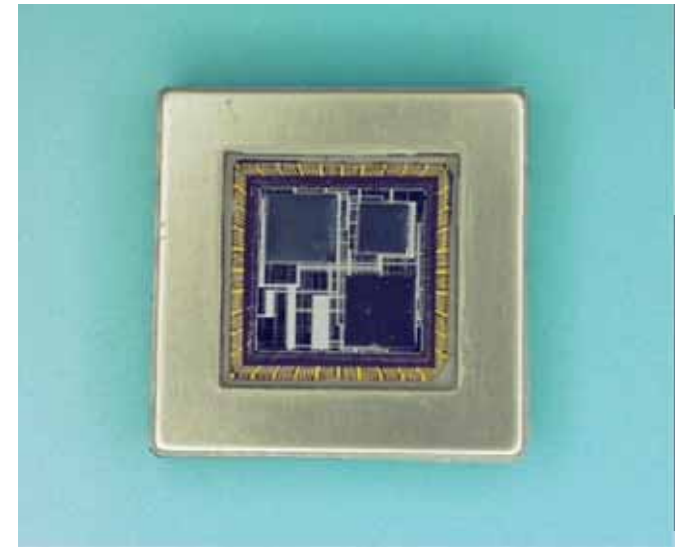
■ Advantage

Variable memory capacity/supplier
Possible for memory shrink

10. Next Generation SiP Technology (CoC Technology)

Benefits of CoC Technology(Chip on Chip)

- Interchip High-Speed Data Transfer
(CPU-Memory etc.)
- Various kinds device consolidation SiP
- Process Consolidation of Various generation
(maturity + point)
- High density mounting
- Thin making multi chip accumulating PKG

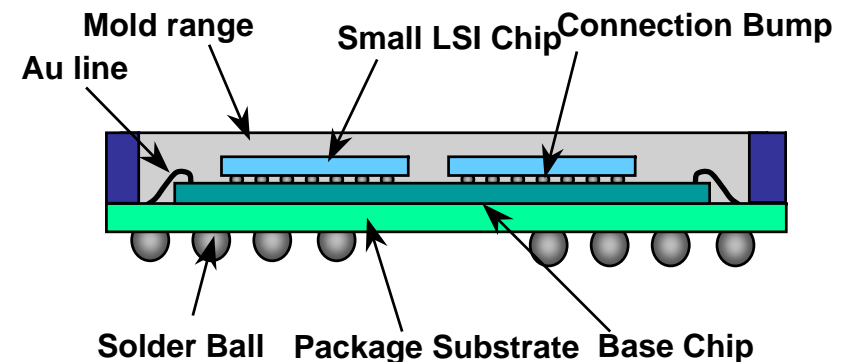


When Base Chip is global wiring Chip

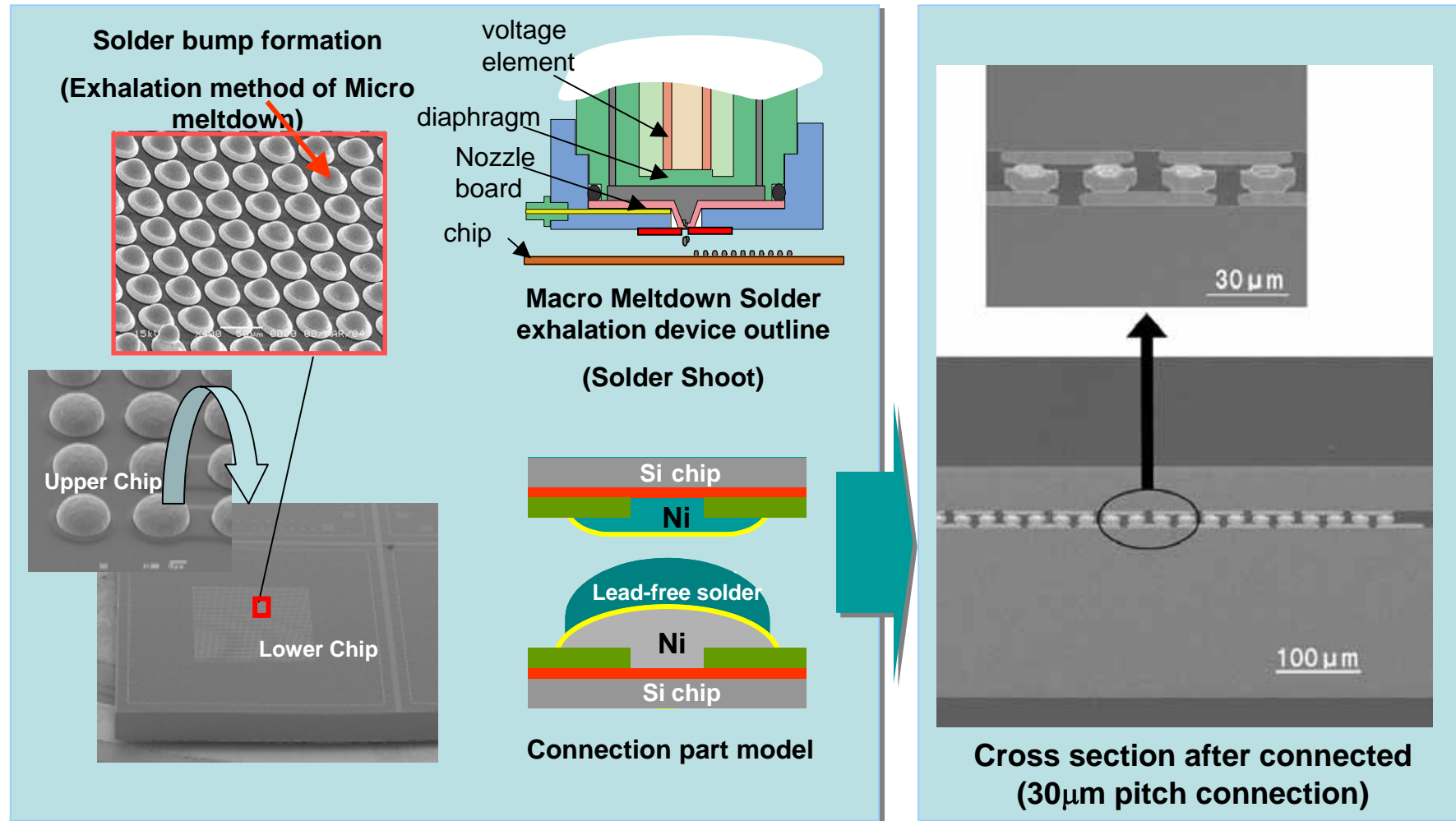
- Minute wiring is unnecessary
Low Cost and Low resisted.

When Base Chip is LSI Chip

- mass memory installable
- Global wiring short able
Improved Switching Characteristics
- Unnecessary output buffer
Reduced Power consumption
- After installed Base Chip, it can be tested.



Minute pitch connection for CoC Technology



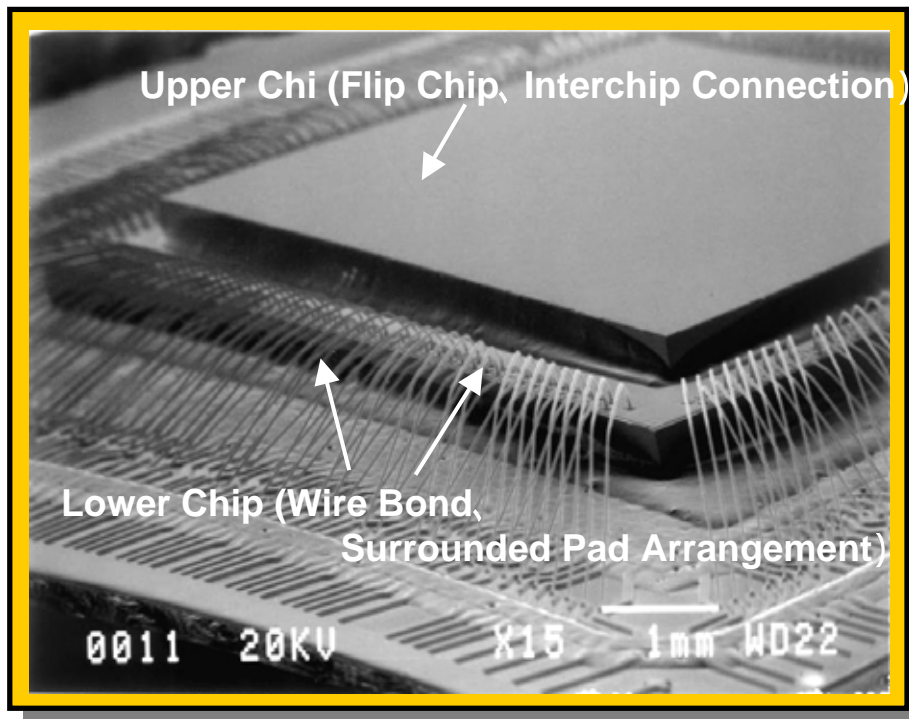
CoC (Chip on Chip) Connection COC(10,000bump)

Technology of Chip to Chip

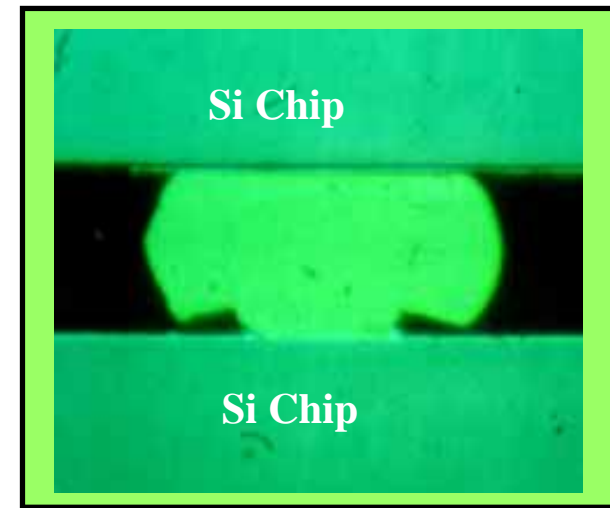
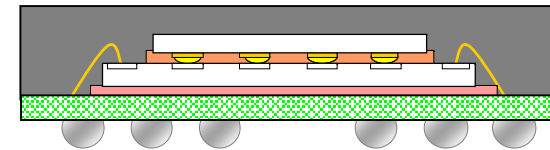
Substrate NET Reduction by LSI Development only for SiP
For High-speed Operation

(Improvement of data Transfer rate)

Digital and Analog Separation (Point SoC
Achievement by SiP)



SiPWhole general view observation Ex.



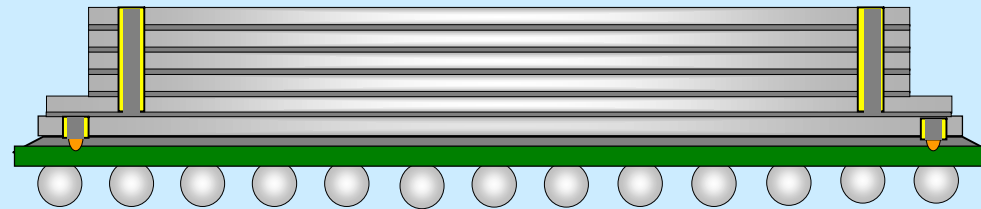
Chip On Chip Connection

11. Next Generation SiP Technology (Si Hole-through Technology)

~ Technology for Ultra thin multi stack SiP ~

Development of Si Hole-through connection Technology**

■ 3-D SiP by Si hole-through Connection Technology



**Under Development

■ Advantage

- Connect chip interconnection at standard temperature by caulking technique
- Thickness of Stack SiP PKG is reduced by half

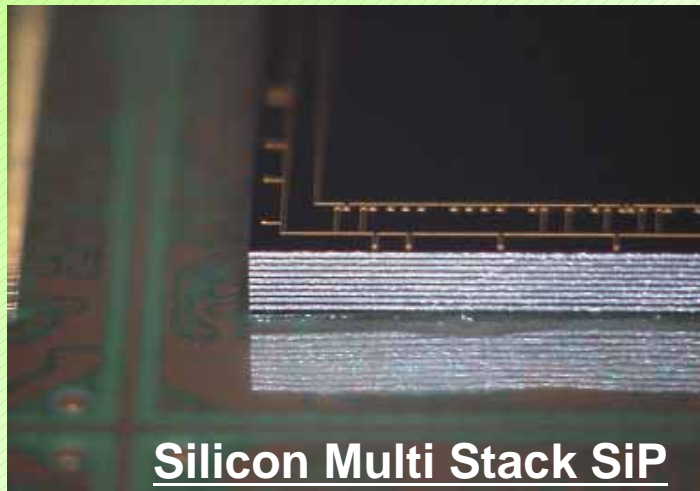
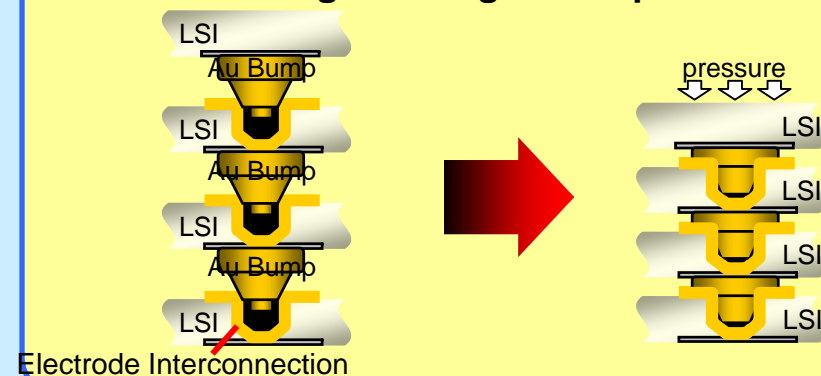
SiP Product TEG with Si hole-through Connection**

~ High Density SiP Technology by 3D Multi Stack ~

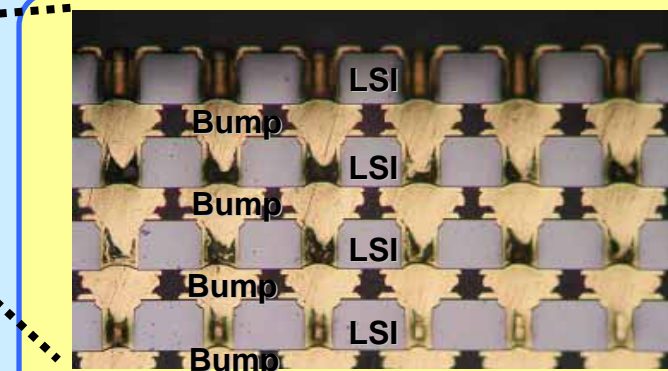
■ Low Cost 3D Silicon Multi SiP Process

Cost for Through Electrode Formation with Standard Temperature Chip interconnection with Caulking Method -> 70%

Room temperature chip to chip interconnection using caulking technique

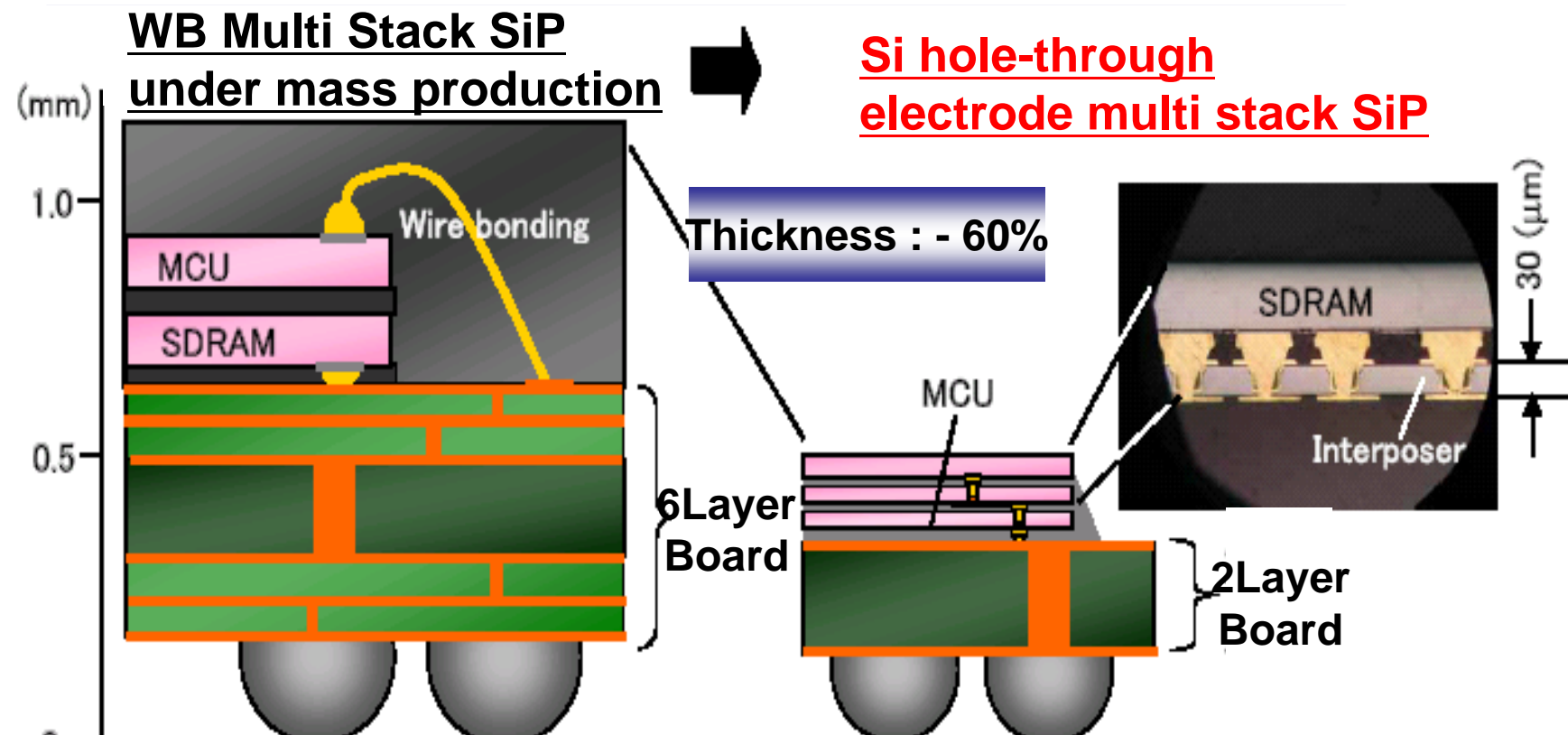


**Under Development



Silicon Multi Stack SiP Cross Section

Realize Small/Think making with Si hole-through connection**

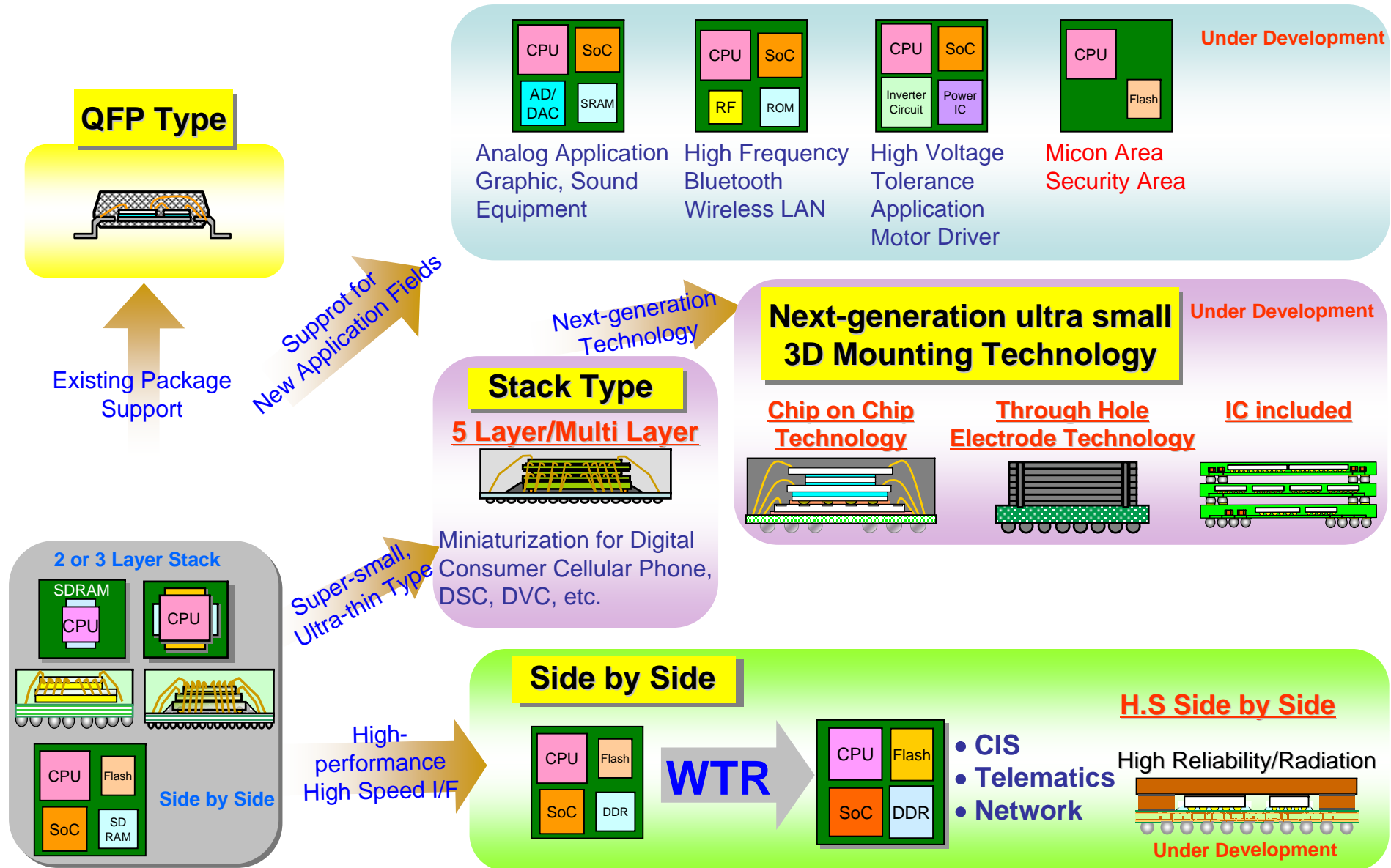


- **Package Thickness : 1.25mm**
- **Package Board : 6 layer (t=0.46 mm)**
- **Wire Length : Long**
- **Resin-sealed Required**

- **Package Thickness : 0.5mm**
- **Package Board : 2 Layer (t=0.2 mm)**
- **Wire Length : Shortest (WB-less)**
- **Resin-sealed Not-required**

**Under Development

SiP Roadmap





株式会社ルネサス テクノロジ

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